

TPLD1201-Q1 Automotive Programmable Logic Device with 8-GPIO

1 Features

- Operating characteristics
 - Extended temperature range: -40°C to 125°C
 - Wide supply voltage range: 1.71V to 5.5V
 - Qualified for automotive applications
- Configurable macro-cells
 - 2-, 3-, and 4-bit lookup tables
 - D-type flip-flops and latches with and without reset/set option
 - 8-bit pipe delay
 - Counters and delay generator
 - Programmable deglitch filter or edge detector
 - Discrete analog comparators
 - Voltage reference
 - Oscillator
- Flexible digital I/O features
 - All digital signals can be routed to any GPIO
 - Digital input modes: digital in with and without Schmitt-trigger, low-voltage digital in
 - Digital output modes: push-pull, open-drain NMOS, tri-state
- Development tools
 - InterConnect Studio
 - TPLD1201-Q1 evaluation module
 - TPLD programming board

2 Applications

- [Factory automation and control](#)
- [Communications equipment](#)
- [Retail automation and payment](#)
- [Test and measurement](#)
- [Pro audio, video and signage](#)
- [Personal electronics](#)
- [Automotive](#)

3 Description

The TPLD1201-Q1 is part of the TI programmable logic device (TPLD) family of devices that feature versatile programmable logic ICs with combinational logic, sequential logic, and analog blocks. TPLD provides a fully integrated, low power solution to implement common system functions, such as timing delays, voltage monitors, system resets, power sequencers, I/O expanders, and more. This device features configurable I/O structures that extends compatibility within mixed-signal environments, reducing the number of discrete components required.

System designers can create circuits and configure the macro-cells, I/O pins, and interconnections by temporarily emulating the non-volatile memory or by permanently programming the one-time programmable (OTP) through InterConnect Studio. The TPLD1201-Q1 is supported by a hardware and software ecosystem with application notes, reference designs, and design examples. Visit ti.com for more information and access to design tools.

Device Information

PART NUMBER	PACKAGE ⁽¹⁾	BODY SIZE (NOM)
TPLD1201-Q1	DGS (VSSOP, 10)	4.9mm × 3.0mm

(1) For all available packages, see the orderable addendum at the end of the datasheet.

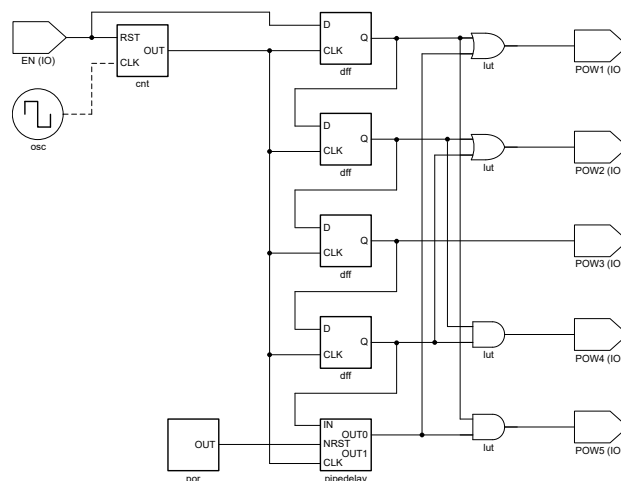


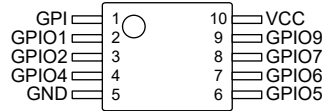
Figure 3-1. Simplified Application



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4 Pin Configuration and Functions



Not to scale

Figure 4-1. DGS Package, 10-Pin VSSOP (Top View)

Table 4-1. Pin Functions

PIN			DESCRIPTION	
NAME	DGS	TYPE ⁽¹⁾	Primary function	Secondary function (if any)
GPI	1	I	General-purpose input ⁽²⁾	
IO1	2	I/O	General-purpose I/O	ACMP0 IN+
IO2	3	I/O	General-purpose I/O	External VREF IN/ACMP0 or ACMP1 IN-
IO4	4	I/O	General-purpose I/O with output enable (OE) ⁽³⁾	ACMP1 IN+
GND	5	P	Ground	
IO5	6	I/O	General-purpose I/O	
IO6	7	I/O	General-purpose I/O	
IO7	8	I/O	General-purpose I/O with output enable (OE) ⁽³⁾	Internal VREF OUT
IO9	9	I/O	General-purpose I/O	External OSC IN
VCC	10	P	Supply voltage	

(1) P = power, I/O = input/output, I = Input

(2) The general-purpose input (GPI) pin will sustain a high-voltage (VPP) during programming. Take special precaution with peripherals connected to this pin if performing in-system programming.

(3) The output enable (OE) connection is available through the connection mux and can be configured in InterConnect Studio.

5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

		MIN	MAX	UNIT
V _{CC}	Supply voltage on V _{CC} relative to GND	-0.5	7	V
V _I	Input voltage	-0.5	V _{CC} + 0.5	V
V _O	Output voltage	-0.5	V _{CC} + 0.5	V
I _{IOK}	Input-output clamp current	V _{IO} < 0 or V _{IO} > V _{CC}		mA
I _O	Continuous output current	V _O = 0 to V _{CC}		mA
I _{DC}	Maximum average or DC current (through each pin)	Push-pull 1X		mA
		Push-pull 2X		
		Open-drain NMOS 1X		
		Open-drain NMOS 2X		
T _J	Junction temperature		150	°C
T _{stg}	Storage temperature	-65	150	°C

- (1) Operation outside the *Absolute Maximum Ratings* may cause permanent device damage. Absolute Maximum Ratings do not imply functional operation of the device at these or any other conditions beyond those listed under *Recommended Operating Conditions*. If used outside the *Recommended Operating Conditions* but within the *Absolute Maximum Ratings*, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime.

5.2 ESD Ratings

			VALUE	UNIT
V _(ESD)	Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins ⁽¹⁾	±2000	V
		Charged device model (CDM), per ANSI/ESDA/JEDEC specification JS-002, all pins ⁽²⁾	±1500	

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

5.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		V _{CC}	MIN	MAX	UNIT
V _{CC}	Supply voltage		1.71	5.5	V
V _I	Input voltage		0	V _{CC}	V
V _O	Output voltage		0	V _{CC}	V
V _{AI}	Analog input voltage	Positive input (ACMP IN+)	0	V _{CC}	V
		Negative input (ACMP IN-, Ext. VREF)	0.15	1.2	
V _{IH}	High-level input voltage	Logic input	1.71V to 5.5V	0.7 × V _{CC}	V
		Low-voltage logic input	1.8V ± 0.09V	0.95	
		Low-voltage logic input	3.3V ± 0.3V	1.2	
		Low-voltage logic input	5V ± 0.5V	1.3	
V _{IL}	Low-level input voltage	Logic input	1.71V to 5.5V	0.3 × V _{CC}	V
		Low-voltage logic input	1.8V ± 0.09V	0.40	
		Low-voltage logic input	3.3V ± 0.3V	0.55	
		Low-voltage logic input	5V ± 0.5V	0.65	
F _(EXT)	External Oscillator Frequency		1.8V ± 0.09V	8	MHz
			3.3V ± 0.3V	8	
			5V ± 0.5V	8	

over operating free-air temperature range (unless otherwise noted)

		V _{CC}	MIN	MAX	UNIT
T _A	Ambient temperature		-40	125	°C

5.4 Thermal Information

THERMAL METRIC ⁽¹⁾		TPLD1201			
		DGS (VSSOP)			
		10-PIN			
			MIN	MAX	UNIT
R _{θJA}	Junction-to-ambient thermal resistance		152.7		°C/W
R _{θJC(top)}	Junction-to-case (top) thermal resistance		60.8		°C/W
R _{θJB}	Junction-to-board thermal resistance		88.9		°C/W
Ψ _{JT}	Junction-to-top characterization parameter		4.8		°C/W
Ψ _{JB}	Junction-to-board characterization parameter		87.2		°C/W
R _{θJC(bot)}	Junction-to-case (bottom) thermal resistance				°C/W

(1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report.

5.5 Electrical Characteristics

over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
Supply and Power-on Reset							
V _{PORR}	Power-on reset voltage, V _{CC} rising	V _I = V _{CC} or GND, I _O = 0	1.71V to 5.5V	1.30	1.31	1.35	V
V _{PORF}	Power-on reset voltage, V _{CC} falling	V _I = V _{CC} or GND, I _O = 0	1.71V to 5.5V	1.25	1.27	1.30	V
t _{SU}	Startup time	from V _{CC} rising past V _{PORR}	1.71V to 5.5V		270		μs
V _{PP}	Programming voltage			7.5	8	8.5	V
Digital IO							
V _{T+}	Positive-going input threshold voltage	Logic Input with Schmitt Trigger	1.8V ± 0.09V	0.94		1.27	V
			3.3V ± 0.3V	1.55		2.17	
			5V ± 0.5V	2.21		3.19	
V _{T-}	Negative-going input threshold voltage	Logic Input with Schmitt Trigger	1.8V ± 0.09V	0.58		0.94	V
			3.3V ± 0.3V	1.1		1.79	
			5V ± 0.5V	1.63		2.7	
V _{HYS}	Schmitt trigger hysteresis (V _{T+} - V _{T-})	Logic Input with Schmitt Trigger	1.8V ± 0.09V	0.25		0.47	V
			3.3V ± 0.3V	0.33		0.54	
			5V ± 0.5V	0.42		0.66	
V _{HYS}	GPI Hysteresis Voltage	Hysteresis voltage applicable to the IN0	1.71V to 5.5V			0.2	V

over operating free-air temperature range (unless otherwise noted)

PARAMETER			TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT			
V _{OH}	High-level output voltage	Push-pull 1X or Open-drain PMOS 1X	I _{OH} = -100μA	1.8V ± 0.09V	1.68			V			
		Push-pull 2X or Open-drain PMOS 2X			1.69						
		Push-pull 1X or Open-drain PMOS 1X	I _{OH} = -3mA	3.3V ± 0.3V	2.60						
		Push-pull 2X or Open-drain PMOS 2X			2.75						
		Push-pull 1X or Open-drain PMOS 1X	I _{OH} = -5mA	5V ± 0.5V	3.99						
		Push-pull 2X or Open-drain PMOS 2X			4.16						
V _{OL}	Low-level output voltage	Push-pull 1X	I _{OL} = 100μA	1.8V ± 0.09V	0.01			V			
		Push-pull 2X			0.01						
		Open-drain NMOS 1X			0.01						
		Open-drain NMOS 2X			0.01						
		Push-pull 1X	I _{OL} = 3mA	3.3V ± 0.3V	0.1						
		Push-pull 2X			0.1						
		Open-drain NMOS 1X			0.1						
		Open-drain NMOS 2X			0.1						
		Push-pull 1X	I _{OL} = 5mA	5V ± 0.5V	0.12						
		Push-pull 2X			0.12						
		Open-drain NMOS 1X			0.12						
		Open-drain NMOS 2X			0.12						
		I _{OZ}	Off-state (high-Z state) output current	IO1, IO2, IO5, IO6, IO9	V _O = 0 to 5.5V						μA
		F _{OUT}	Max output frequency ⁽¹⁾	Push-pull 1X or Push-pull 2X	15pF Load capacitance	1.8V ± 0.09V				5	MHz
3.3V ± 0.3V							12				
5V ± 0.5V							12				
R _{pu(int)}	Internal pull-up resistance					1		MΩ			
						100		kΩ			
						10		kΩ			
R _{pd(int)}	Internal pull-down resistance					1		MΩ			
						100		kΩ			
						10		kΩ			
C _I	Input pin capacitance	each input pin	V _I = V _{CC} or GND	1.71V to 5.5V		1.2		pF			
C _{IO}	Input-output pin capacitance	each I/O pin	V _{IO} = V _{CC} or GND	1.71V to 5.5V		2.0		pF			
Analog Comparator											
t _{start}	Start time	ACMP power on delay	Bandgap always on	1.71V to 5.5V		150		μs			
V _{AI}	Input voltage	Positive input		1.71V to 5.5V	0		V _{CC}	V			
		Negative input			0		1.2				
V _{offset}	Input offset voltage	T _A = 25°C	V _{HYS} = 0 mV, Gain = 1, VREF = 50mV - 1200mV	1.71V to 5.5V	-6		6	mV			
		-40°C < T _A ≤ 125°C			-7		7				

over operating free-air temperature range (unless otherwise noted)

PARAMETER			TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
dV _{IO} /dT	Input offset voltage drift	-40°C < T _A ≤ 125°C	V _{HYS} = 0 mV, Gain = 1, VREF = 50mV - 1200mV	1.71V to 5.5V		±7		μV/°C
I _B	Input bias current						1	μA
C _{ID}	Input capacitance, differential					3		pF
C _{IM}	Input capacitance, common mode					3		pF
PROP	Propagation delay, response time	Gain = 1, Vref = 50mV - 1200mV, Overdrive = 50mV	Low to High, Low bandwidth enabled	1.71V to 5.5V	2.5			μs
			High to Low Low bandwidth enabled		2.5			
			Low to High, Low bandwidth disabled		0.25			
			High to Low Low bandwidth disabled		0.25			
Analog Comparator - Hysteresis								
V _{HYS}	Built-in hysteresis	V _{HYS} = 25mV	T _A = 25°C	1.71V to 5.5V	20	25	30	mV
			-40°C to 125°C		18.75	25	31.25	
		V _{HYS} = 50mV	T _A = 25°C		40	50	60	
			-40°C to 125°C		37.5	50	62.5	
		V _{HYS} = 200mV	T _A = 25°C		160	200	240	
			-40°C to 125°C		150	200	250	
Analog Comparator - Input Gain								
R _{sin}	Series input resistance	Gain = 0.5	1.71V to 5.5V	1	MΩ			
		Gain = 0.33		0.75				
		Gain = 0.25		1				
G _{err}	Gain error	Gain = 0.5	1.71V to 5.5V	-1	1	%		
		Gain = 0.33		-1.5	1.5			
		Gain = 0.25		-2	2			
Voltage Reference								
VREF	VREF error	T _A = 25°C	VREF = 150mV - 300mV	1.71V to 5.5V	-10.2	1	10.2	%
		-40°C < T _A ≤ 125°C			-11	1	11	
		T _A = 25°C	VREF = 350mV - 600mV		-5	0.9	5	
		-40°C < T _A ≤ 125°C			-5.5	0.9	5.5	
		T _A = 25°C	VREF = 650mV - 1000mV		-3.3	0.9	3.3	
		-40°C < T _A ≤ 125°C			-4.3	0.9	4.3	
		T _A = 25°C	VREF = 1050mV - 1200mV		-3	0.85	3	
		-40°C < T _A ≤ 125°C			-5	0.85	5	

ADVANCE INFORMATION

over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT				
VREF	Internal VREF error	T _A = 25°C	1.71V to 5.5V				%				
		-40°C < T _A ≤ 125°C						VREF = 150mV - 300mV	-3.1	1	3.1
		T _A = 25°C						VREF = 350mV	-4.3	1	4.3
		-40°C < T _A ≤ 125°C						- 600mV	-3	0.95	3
		T _A = 25°C						VREF = 650mV	-4	0.95	4
		-40°C < T _A ≤ 125°C						- 1000mV	-2.5	0.9	2.5
		T _A = 25°C	VREF = 1050mV - 1200mV								
		-40°C < T _A ≤ 125°C									
I _{LOAD}	Output Current		1.71V to 5.5V			500	μA				
dV _{OUT} /dT	Output voltage temperature drift		1.71V to 5.5V			550	ppm/°C				
dV _{OUT} /dI _{LOAD}	Load regulation		1.71V to 5.5V		0.1	1	mV/μA				

(1) Open drain switching performance will be limited by pull-up resistors used

5.6 Supply Current Characteristics

 T_A = 25°C (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V _{CC} = 1.8V ± 0.09V			V _{CC} = 3.3V ± 0.3V			V _{CC} = 5V ± 0.5V			UNIT	
				MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	
Standby													
I _{CC}	Quiescent current	Inputs = static, Outputs = open, I _O = 0, OSC powered off			3.41			3.66			4.00		μA
Oscillator													
I _{CC}	Quiescent current	OSC0 enabled: 25kHz	Predivide = 1		3.21		5.24		13.2				μA
			Predivide = 2		3.14		5.17		13.2				
			Predivide = 4		3.08		5.11		13.1				
			Predivide = 8		3.08		5.11		13.1				
		OSC0 enabled: 2MHz	Predivide = 1		42.9		56.0		104.0				
			Predivide = 2		35.9		49.0		97.0				
			Predivide = 4		32.5		45.6		93.6				
			Predivide = 8		30.7		43.8		91.8				
Analog Comparator													
I _{CC}	Quiescent current	Discrete analog comparator (ACMP)	External VREF, IN+ = 0V		25.0		26.6		27.6				μA
		Discrete analog comparator (ACMP)	Additional ACMP		4.26		4.08		4.23				
Voltage Reference													
I _{CC}	Quiescent current	Voltage reference (VREF)			16.3		16.7		17.3				μA

5.7 Switching Characteristics

T_A = 25°C (unless otherwise noted)

PARAMETER			V _{CC}	MIN	TYP	MAX	UNIT
Digital IO							
t _{pd}	Delay	Digital input without Schmitt trigger to Push-pull output - Rising	1.8V ± 0.09V	34.9		ns	
		Digital input without Schmitt trigger to Push-pull output - Falling		30.8			
		Digital input without Schmitt trigger to Push-pull output - Rising	3.3V ± 0.3V	20.3			
		Digital input without Schmitt trigger to Push-pull output - Falling		20.7			
		Digital input without Schmitt trigger to Push-pull output - Rising	5V ± 0.5V	16.4			
		Digital input without Schmitt trigger to Push-pull output - Falling		17.7			
t _{pd}	Delay	Digital input with Schmitt trigger to Push-pull output - Rising	1.8V ± 0.09V	38.6		ns	
		Digital input with Schmitt trigger to Push-pull output - Falling		32.8			
		Digital input with Schmitt trigger to Push-pull output - Rising	3.3V ± 0.3V	22.6			
		Digital input with Schmitt trigger to Push-pull output - Falling		21.5			
		Digital input with Schmitt trigger to Push-pull output - Rising	5V ± 0.5V	18.3			
		Digital input with Schmitt trigger to Push-pull output - Falling		18.0			
t _{pd}	Delay	Low-voltage digital input to Push-pull output - Rising	1.8V ± 0.09V	30.5		ns	
		Low-voltage digital input to Push-pull output - Falling		33.3			
		Low-voltage digital input to Push-pull output - Rising	3.3V ± 0.3V	17.9			
		Low-voltage digital input to Push-pull output - Falling		22.3			
		Low-voltage digital input to Push-pull output - Rising	5V ± 0.5V	14.0			
		Low-voltage digital input to Push-pull output - Falling		19.9			
t _{pd}	Delay	Digital input without Schmitt trigger to Open drain NMOS output - Rising	1.8V ± 0.09V	50.6		ns	
		Digital input without Schmitt trigger to Open drain NMOS output - Falling		25.9			
		Digital input without Schmitt trigger to Open drain NMOS output - Rising	3.3V ± 0.3V	21.6			
		Digital input without Schmitt trigger to Open drain NMOS output - Falling		16.8			
		Digital input without Schmitt trigger to Open drain NMOS output - Rising	5V ± 0.5V	14.2			
		Digital input without Schmitt trigger to Open drain NMOS output - Falling		14.0			
t _{pd}	Delay	Output enable from pin, OE, Hi-Z to 1 - Rising	1.8V ± 0.09V	45.2		ns	
			1.8V ± 0.09V	27.7			
			3.3V ± 0.3V	22.7			
t _{pd}	Delay	Output enable from pin, OE, Hi-Z to 0 - Falling	3.3V ± 0.3V	43.2		ns	
			5V ± 0.5V	20.6			
			5V ± 0.5V	20.6			
Configurable Use Logic							

ADVANCE INFORMATION

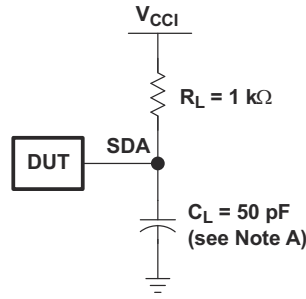
$T_A = 25^\circ\text{C}$ (unless otherwise noted)

PARAMETER			V_{CC}	MIN	TYP	MAX	UNIT
t_{pd}	Delay	2-bit LUT - Rising	$1.8V \pm 0.09V$	1.14		ns	
		2-bit LUT - Falling		1.32			
		2-bit LUT - Rising	$3.3V \pm 0.3V$	1.14			
		2-bit LUT - Falling		1.31			
		2-bit LUT - Rising	$5V \pm 0.5V$	1.16			
		2-bit LUT - Falling		1.35			
t_{pd}	Delay	3-bit LUT - Rising	$1.8V \pm 0.09V$	1.31		ns	
		3-bit LUT - Falling		1.53			
		3-bit LUT - Rising	$3.3V \pm 0.3V$	1.31			
		3-bit LUT - Falling		1.53			
		3-bit LUT - Rising	$5V \pm 0.5V$	1.31			
		3-bit LUT - Falling		1.53			
t_{pd}	Delay	4-bit LUT - Rising	$1.8V \pm 0.09V$	1.53		ns	
		4-bit LUT - Falling		1.86			
		4-bit LUT - Rising	$3.3V \pm 0.3V$	1.53			
		4-bit LUT - Falling		1.86			
		4-bit LUT - Rising	$5V \pm 0.5V$	1.53			
		4-bit LUT - Falling		1.86			
t_{pd}	Delay	Latch with nRST/nSET - Rising	$1.8V \pm 0.09V$	1.58		ns	
		Latch with nRST/nSET - Falling		1.58			
		Latch with nRST/nSET - Rising	$3.3V \pm 0.3V$	1.58			
		Latch with nRST/nSET - Falling		1.58			
		Latch with nRST/nSET - Rising	$5V \pm 0.5V$	1.58			
		Latch with nRST/nSET - Falling		1.58			
Counter/Delay							
t_{pd}	Delay	CNT/DLY - Rising	$1.8V \pm 0.09V$	2.21		ns	
		CNT/DLY - Falling		2.01			
		CNT/DLY - Rising	$3.3V \pm 0.3V$	2.21			
		CNT/DLY - Falling		2.01			
		CNT/DLY - Rising	$5V \pm 0.5V$	2.21			
		CNT/DLY - Falling		2.01			
Oscillator							
f_{err}	Oscillator frequency error	OSC025 kHz	$1.8V \pm 0.09V$	-5	5	%	
			$3.3V \pm 0.3V$	-5	5		
			$5V \pm 0.5V$	-5	5		
f_{err}	Oscillator frequency error	OSC0 2MHz	$1.8V \pm 0.09V$	-5	5	%	
			$3.3V \pm 0.3V$	-5	5		
			$5V \pm 0.5V$	-5	5		
t_{d_osc}	Oscillator startup delay	OSC0 25 kHz (Auto power on)	$1.8V \pm 0.09V$	32.7		μs	
			$3.3V \pm 0.3V$	33.1			
			$5V \pm 0.5V$	33.4			
t_{d_osc}	Oscillator startup delay	OSC0 2MHz (Auto power on)	$1.8V \pm 0.09V$	4.5		μs	
			$3.3V \pm 0.3V$	4.9			
			$5V \pm 0.5V$	5.2			

T_A = 25°C (unless otherwise noted)

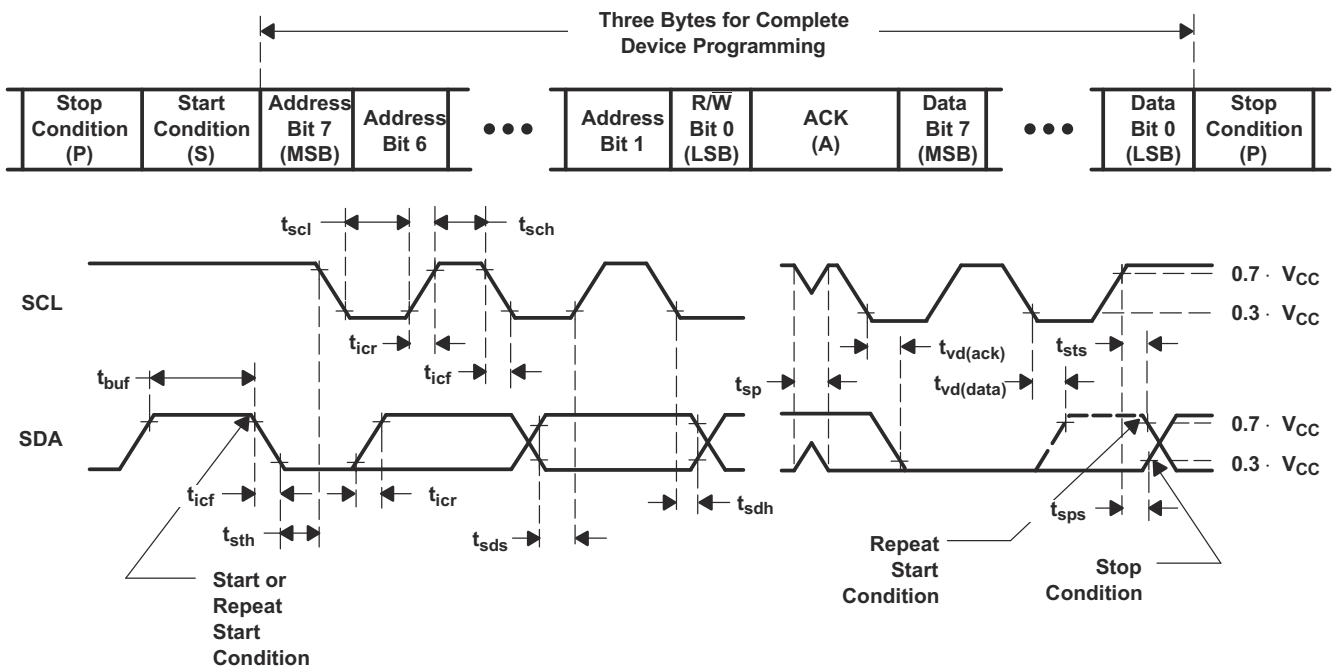
PARAMETER			V _{CC}	MIN	TYP	MAX	UNIT
t _{set_osc}	Oscillator startup settling time	OSC0 25kHz (Auto power on)	1.8V ± 0.09V		1		µs
			3.3V ± 0.3V		1		
			5V ± 0.5V		1		
t _{set_osc}	Oscillator startup settling time	OSC0 2MHz (Auto power on)	1.8V ± 0.09V		7		µs
			3.3V ± 0.3V		7		
			5V ± 0.5V		7		
t _{d_err}	Delay error	OSC (Forced power on)	1.71V to 5.5V	0		1	CLK cycle
Programmable Filter							
t _{pflt_pw}	Pulse width, 1 cell	PFLT mode: (any) edge detect, edge detect output	1.8V ± 0.09V		154.0		ns
			3.3V ± 0.3V		157.3		
			5V ± 0.5V		158.7		
	Pulse width, 2 cells	PFLT mode: (any) edge detect, edge detect output	1.8V ± 0.09V		256.2		ns
			3.3V ± 0.3V		259.7		
			5V ± 0.5V		260.8		
	Pulse width, 3 cells	PFLT mode: (any) edge detect, edge detect output	1.8V ± 0.09V		356.2		ns
			3.3V ± 0.3V		360.3		
			5V ± 0.5V		361.5		
Pulse width, 4 cells	PFLT mode: (any) edge detect, edge detect output	1.8V ± 0.09V		455.3		ns	
		3.3V ± 0.3V		459.6			
		5V ± 0.5V		461.4			
t _{pflt_pd}	Delay, any cells	PFLT mode: (any) edge detect, edge detect output	1.8V ± 0.09V		22.0		ns
			3.3V ± 0.3V		21.4		
			5V ± 0.5V		21.3		
t _{pflt_d}	Delay, 1 cell	PFLT mode: both edge delay (shared macrocell inputs)	1.8V ± 0.09V		176.0		ns
			3.3V ± 0.3V		178.7		
			5V ± 0.5V		180.0		
	Delay, 2 cells	PFLT mode: both edge delay (shared macrocell inputs)	1.8V ± 0.09V		278.2		ns
			3.3V ± 0.3V		281.1		
			5V ± 0.5V		282.1		
	Delay, 3 cells	PFLT mode: both edge delay (shared macrocell inputs)	1.8V ± 0.09V		378.2		ns
			3.3V ± 0.3V		281.7		
			5V ± 0.5V		382.8		
	Delay, 4 cells	PFLT mode: both edge delay (shared macrocell inputs)	1.8V ± 0.09V		477.3		ns
			3.3V ± 0.3V		481.0		
			5V ± 0.5V		482.7		

6 Parameter Measurement Information



SDA LOAD CONFIGURATION

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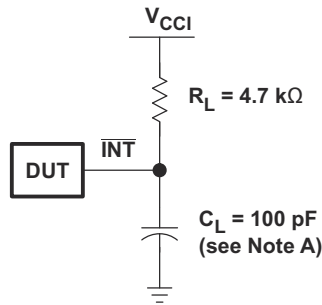


VOLTAGE WAVEFORMS

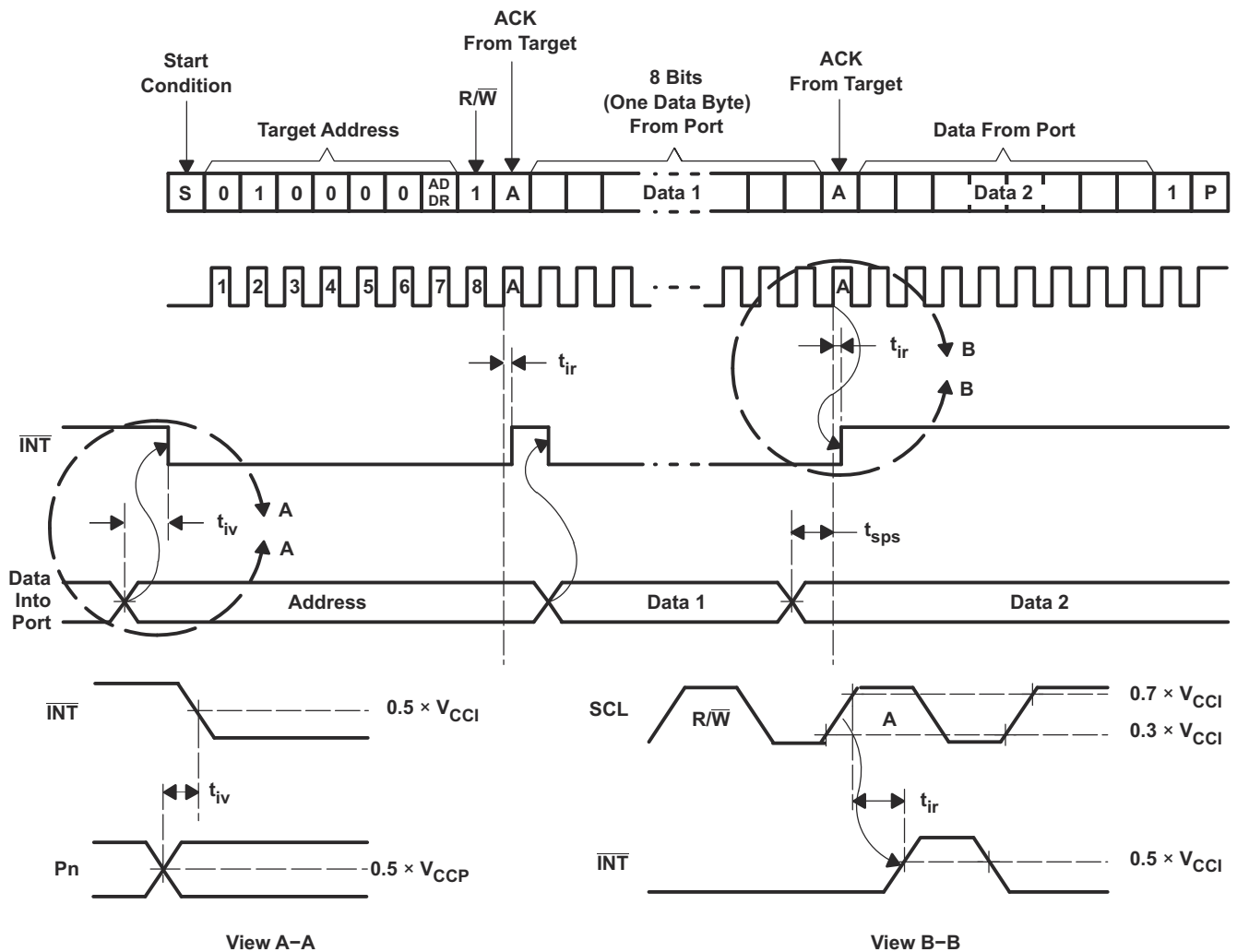
BYTE	DESCRIPTION
1	I ² C address
2, 3	P-port data

- A. C_L includes probe and jig capacitance. t_{cof} is measured with C_L of 10 pF or 400 pF.
- B. All inputs are supplied by generators having the following characteristics: $PRR \leq 10$ MHz, $Z_O = 50 \Omega$, $t_r/t_f \leq 30$ ns.
- C. All parameters and waveforms are not applicable to all devices.

Figure 6-1. I²C Interface Load Circuit and Voltage Waveforms



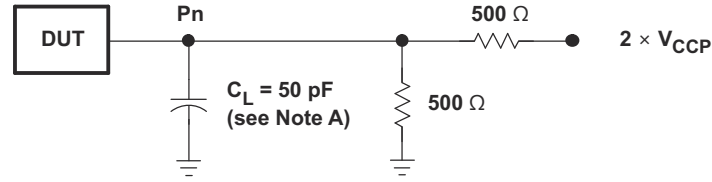
INTERRUPT LOAD CONFIGURATION



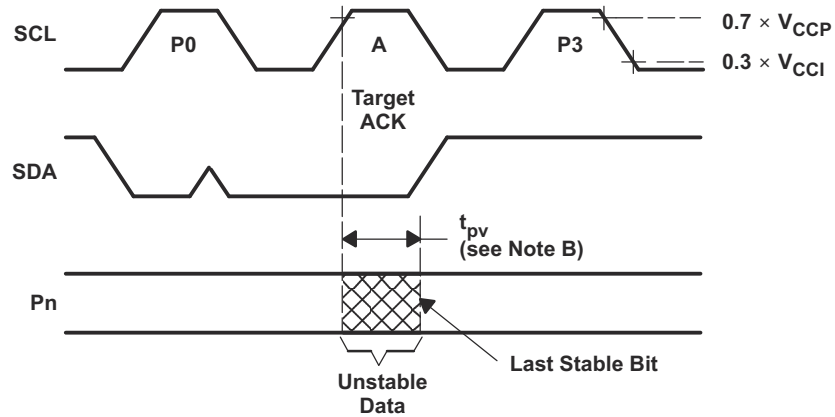
ADVANCE INFORMATION

- A. C_L includes probe and jig capacitance.
- B. All inputs are supplied by generators having the following characteristics: $PRR \leq 10$ MHz, $Z_O = 50 \Omega$, $t_r/t_f \leq 30$ ns.
- C. All parameters and waveforms are not applicable to all devices.

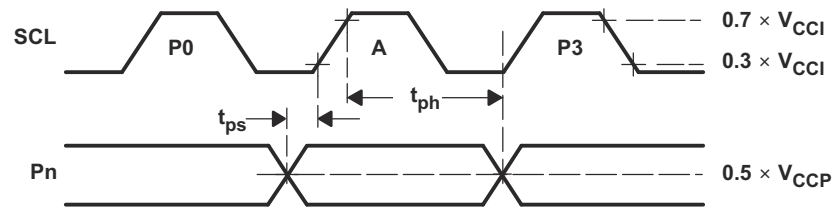
Figure 6-2. Interrupt Load Circuit and Voltage Waveforms



P-PORT LOAD CONFIGURATION



WRITE MODE ($R/\bar{W} = 0$)

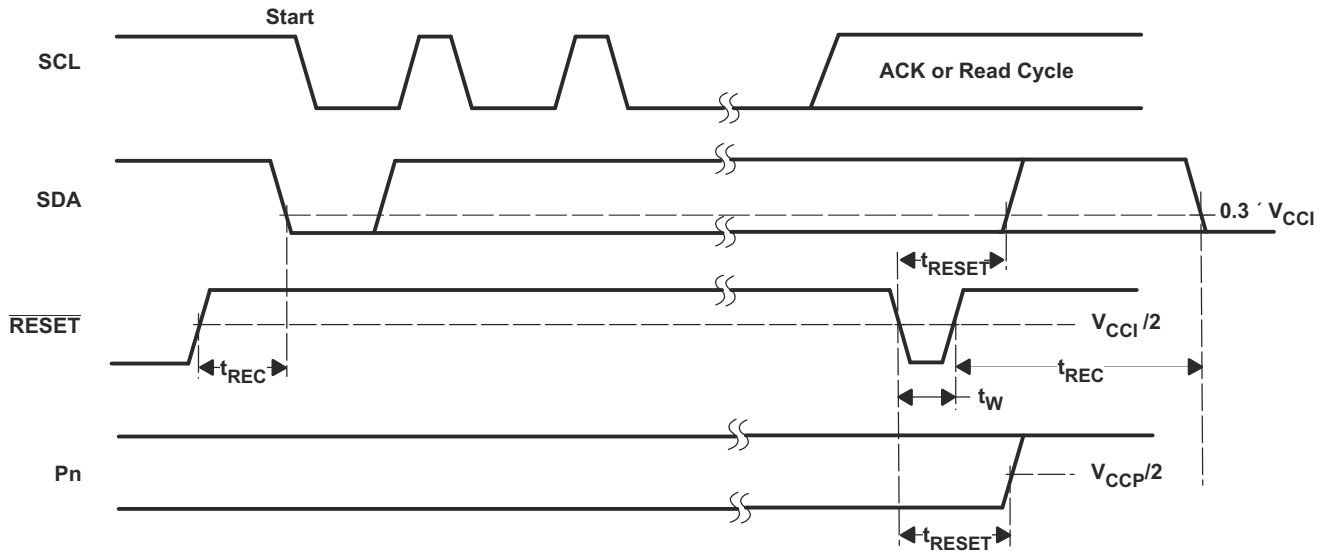
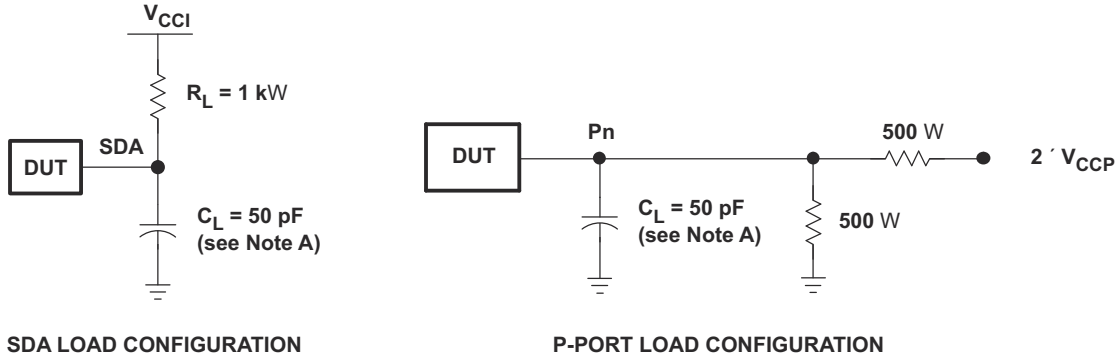


READ MODE ($R/\bar{W} = 1$)

- A. C_L includes probe and jig capacitance.
- B. t_{pv} is measured from $0.7 \times V_{CC}$ on SCL to 50% I/O (P_n) output.
- C. All inputs are supplied by generators having the following characteristics: $PRR \leq 10$ MHz, $Z_O = 50 \Omega$, $t_r/t_f \leq 30$ ns.
- D. The outputs are measured one at a time, with one transition per measurement.
- E. All parameters and waveforms are not applicable to all devices.

Figure 6-3. P-Port Load Circuit and Timing Waveforms

ADVANCE INFORMATION



- A. C_L includes probe and jig capacitance.
- B. All inputs are supplied by generators having the following characteristics: $PRR \leq 10$ MHz, $Z_O = 50 \Omega$, $t_r/t_f \leq 30$ ns.
- C. The outputs are measured one at a time, with one transition per measurement.
- D. I/Os are configured as inputs.
- E. All parameters and waveforms are not applicable to all devices.

Figure 6-4. Reset Load Circuits and Voltage Waveforms

ADVANCE INFORMATION

7 Detailed Description

7.1 Overview

The TPLD1201-Q1 is part of the TI programmable logic device (TPLD) family of devices that feature versatile programmable logic ICs with combinational logic, sequential logic, and analog blocks to provide an integrated, compact, low power solution to implement common system functions.

The TPLD1201-Q1 has one GPI and seven GPIOs that can be configured as a digital input, digital output, digital input or output, or analog input or output.

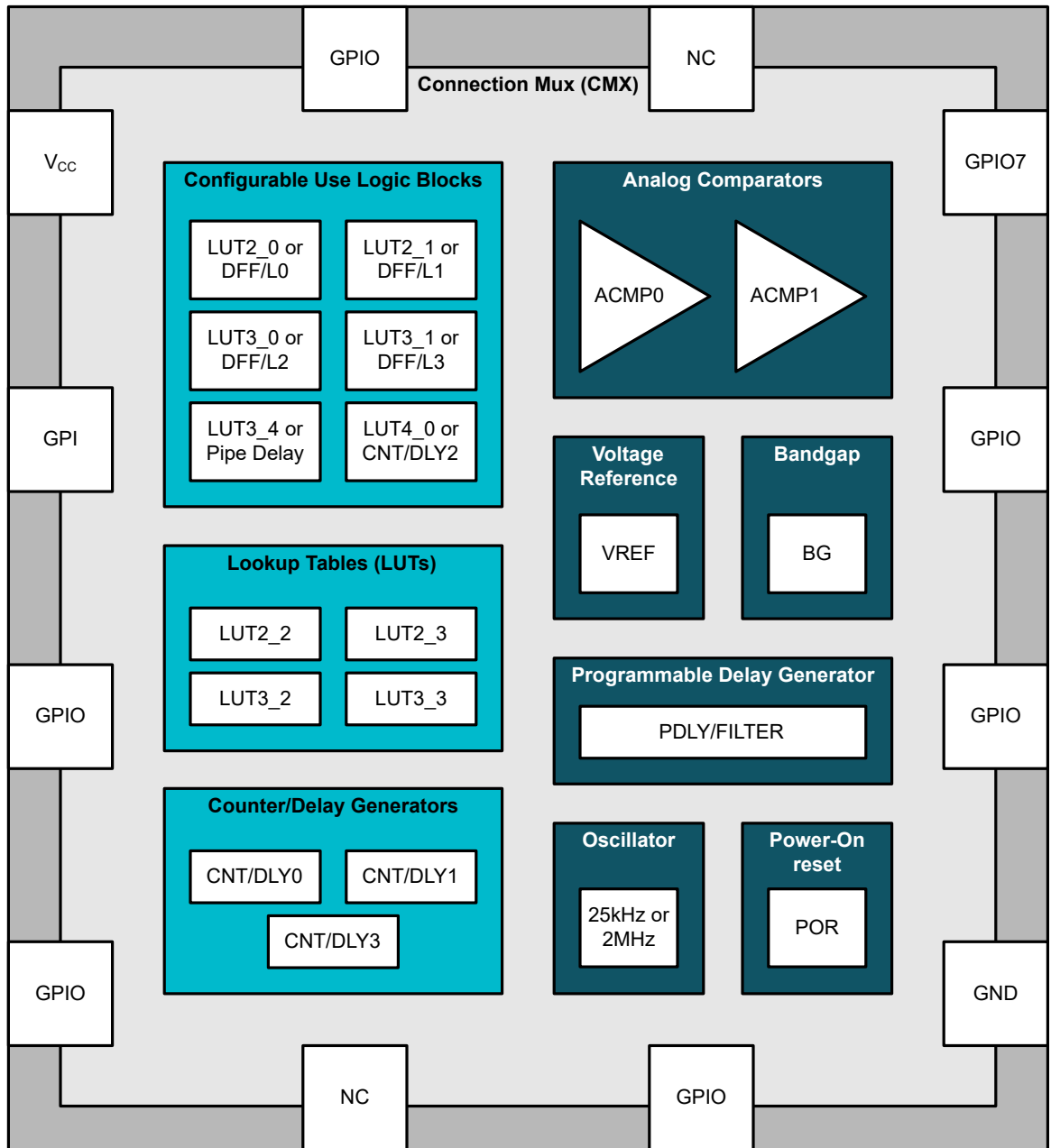
The TPLD1201-Q1 has a system of interconnects, further referred to as the connection mux, to configure the routing of internal macro-cells and I/O pins. Each connection mux input is hardwired to a specific digital macro-cell output, such as digital I/O, lookup tables, and analog comparator outputs. The connection mux allows each of the digital inputs to only connect to one output so that bus contention does not occur.

The TPLD1201-Q1 features the following macro-cells:

- Configurable use logic blocks:
 - Two 2-bit lookup tables (LUT)
 - Two 3-bit LUTs
 - Two 2-bit LUTs or D-type flip-flops (DFF) or latches
 - Two 3-bit LUTs or DFF or latches with reset/set option
 - One 3-bit LUT or Pipe delay
 - One 4-bit LUT or 8-bit counter (CNT) or delay generator (DLY)
- Three 8-bit CNT/DLYs
- One programmable deglitch filter (PFLT) or edge detector (EDET)
- One oscillator (OSC) to generate either a 25kHz or 2MHz clock
- Two analog comparators (ACMP)
- Voltage reference (VREF) with option to output to analog IO

The InterConnect Studio software environment enables a simple drag-and-drop interface to build custom circuit designs and configure the macro-cells, I/O pins, and interconnections. In addition to circuit creation, InterConnect Studio has the ability to simulate digital and analog functionality to verify designs and provide a typical power consumption estimate. Once circuit designs are finalized, InterConnect Studio can temporarily emulate the design in the non-volatile memory or permanently program the one-time programmable (OTP). The OTP can be locked to prevent readback of its contents.

7.2 Functional Block Diagram



ADVANCE INFORMATION

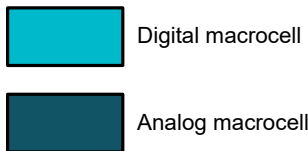


Figure 7-1. TPLD1201-Q1 Functional Block Diagram

7.3 Feature Description

7.3.1 I/O Pins

TPLD1201-Q1 has one input and seven multifunction I/O pins. GPIO pins can function as either a user defined input, output, or a special function.

Input modes: The following options are available when configuring pins as an input:

- Digital input without Schmitt-trigger
- Digital input with Schmitt-trigger
- Low-voltage digital input

The low-voltage digital input has lower V_{IH}/V_{IL} specifications than the digital input without Schmitt trigger. This allows for up-translation from any voltage domain lower than V_{CC} that meets the low-voltage digital input V_{IH} and V_{IL} specifications. The following pins also have the option to function a special function:

- IO9: external clock input
- IO1: positive input of analog comparator 0
- IO2: negative input of analog comparators
- IO4: positive input of analog comparator 1
- IO7: internal voltage reference output

Output modes: The following options are available with programmable drive strength when configuring pins as an output:

- 1x push-pull output
- 2x push-pull output
- 1x open-drain NMOS output
- 2x open-drain NMOS output
- 1x open-drain PMOS output
- 2x open-drain PMOS output

Pull-Up or Pull-Down Resistors: All I/O pins have the option of user-selectable resistors that can be connected to the pin structure. The selectable values on these resistors are 10k Ω , 100k Ω and 1M Ω . The internal resistors can be configured as either pull-up or pull-down. When designing in InterConnect Studio, any pin left unused in a design are configured with a 1M Ω pull-down by default. Furthermore, following a power-on event, all ports are in a Hi-Z state until the power-on reset sequence has completed.

Table 7-1. Pin Configuration Options

GPIO	IO Selection	OE	IO Options	Resistor	Resistor Value
IN0	PIN not used	—	—	Pull-Down	1M Ω
	Digital input	0	Digital in without Schmitt trigger	Floating	—
			Digital in with Schmitt trigger	Pull-Down	10k Ω
			Low-voltage digital input		100k Ω
				1M Ω	

NOTE: GPI/IN0 also has the option to reset the chip while powered on. Unlike POR, External Reset affects only GPI, LUTs, DLY, OSC, DFFs, Latches, Pipe Delay, Matrix, and GPO. NVM remains in its previous state.

Users may select whether the External Reset is *Disabled*, *Level sensitive*, or *Edge triggered*.

When *Level sensitive* is selected, if the input is High, then the device is in reset mode where all internal devices are reset. When this pin goes Low, then the device will begin the reset power on sequence.

When *Edge triggered* is selected, the edge detector can be configured to Rising edge or Falling edge, and an edge on GPI/IN0 resets the device and begins the reset power on sequence.

Table 7-1. Pin Configuration Options (continued)

GPIO	IO Selection	OE	IO Options	Resistor	Resistor Value
IO1, IO2	Pin not used	—	—	Pull Down	1MΩ
	Digital input	0	Digital in without Schmitt trigger Digital in with Schmitt trigger Low-voltage digital input	Floating	—
				Pull-Up	10kΩ
					100kΩ
					1MΩ
				Pull-Down	10kΩ
					100kΩ
	1MΩ				
	Digital output	1	Push-pull (1X, 2X) Open-drain NMOS (1X, 2X) Open-drain PMOS (1X, 2X)	Floating	—
				Pull-Up	10kΩ
					100kΩ
					1MΩ
				Pull-Down	10kΩ
					100kΩ
	1MΩ				
	Digital input/output	0	Analog input	—	—
		1	Open-drain NMOS (1X, 2X)	Floating	—
				Pull-Up	10kΩ
					100kΩ
					1MΩ
Pull-Down				10kΩ	
	100kΩ				
Analog input/output	—	Analog input/output	Floating	—	
			Pull-Up	10kΩ	
				100kΩ	
				1MΩ	
			Pull-Down	10kΩ	
				100kΩ	
1MΩ					

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Table 7-1. Pin Configuration Options (continued)

GPIO	IO Selection	OE	IO Options	Resistor	Resistor Value	
IO4, IO7	Pin not used	—	—	Pull-Down	1MΩ	
	Digital input	0	Digital in without Schmitt trigger Digital in with Schmitt trigger Low-voltage digital input	Floating	—	
				Pull-Up	10kΩ	
					100kΩ	
					1MΩ	
				Pull-Down	10kΩ	
					100kΩ	
	1MΩ					
	Digital output	1/0	Push-pull (1X, 2X) Open-drain NMOS (1X, 2X) 3-state output (1X, 2X)	Floating	—	
				Pull-Up	10kΩ	
					100kΩ	
					1MΩ	
				Pull-Down	10kΩ	
					100kΩ	
	1MΩ					
	Digital input/output	0	Digital in without Schmitt trigger Digital in with Schmitt trigger Low-voltage digital input Analog input (IO4 only)	Floating	—	
				Pull-Up	10kΩ	
					100kΩ	
					1MΩ	
				Pull-Down	10kΩ	
1MΩ						
Analog input/output	—	Analog input/output	Push-pull (1X, 2X) Open-drain NMOS (1X, 2X)	Shared with above		
				Floating	—	
					Pull-Up	10kΩ
						100kΩ
				Pull-Down	10kΩ	
1MΩ						

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Table 7-1. Pin Configuration Options (continued)

GPIO	IO Selection	OE	IO Options	Resistor	Resistor Value
IO5, IO6, IO9	Pin not used	—	—	Pull Down	1MΩ
	Digital input	0	Digital in without Schmitt trigger Digital in with Schmitt trigger Low-voltage digital input	Floating	—
				Pull-Up	10kΩ
					100kΩ
					1MΩ
				Pull-Down	10kΩ
					100kΩ
	1MΩ				
	Digital output	1	Push-pull (1X, 2X) Open-drain NMOS (1X, 2X) Open-drain PMOS (1X, 2X)	Floating	—
				Pull-Up	10kΩ
					100kΩ
					1MΩ
				Pull-Down	10kΩ
100kΩ					
1MΩ					

7.3.2 Connection Mux

The TPLD1201-Q1 has a system of interconnects, referred to as the connection mux, to configure the routing of internal macro-cells and I/O pins. The connection mux has 32 inputs and 44 outputs. Each of the 32 inputs of the connection mux is hardwired to particular macro-cells, including I/O pins, LUTs, analog comparators, other digital resources, VCC, and GND. The input to a digital macro-cell uses a 5-bit register to select one of these 32 input lines.

7.3.3 Configurable Use Logic Blocks

Combinational logic is supported through lookup tables (LUTs) within the TPLD1201-Q1 including two 2-bit LUTs and two 3-bit LUTs. Inputs and outputs for the combination function macro-cells are configured from the connection mux with specific logic functions being defined by the state of OTP bits.

The TPLD1201-Q1 has seven combinational function blocks (macro-cells) that can serve more than one logic or timing function. In each case, they can serve as a lookup table (LUT), or as another logic or timing function. See the following list for the functions that can be implemented in these logic blocks:

- Two 2-bit LUTs
- Two 3-bit LUTs
- Two 2-bit LUTs or D-type flip-flops or latches
- Two 3-bit LUTs or D-type flip-flops or latches with reset/set option
- One 3-bit LUT or Pipe delay
- One 4-bit LUT or 8-bit counter or delay generator

7.3.3.1 2-Bit LUT Macro-Cell

When used to implement LUT functions, the 2-bit LUT takes in two input signals from the connection mux and produces a single output, which goes back into the connection mux.

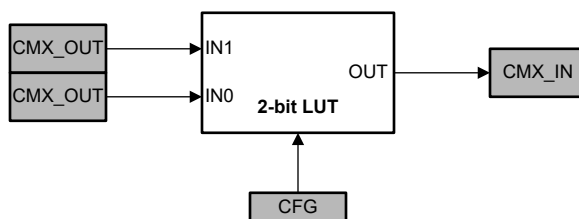


Figure 7-2. 2-Bit LUT Block Diagram

These LUTs can be configured to any 2-input user defined function, including the following standard digital logic functions: AND, NAND, OR, NOR, XOR, XNOR, INV.

Table 7-2 provides the truth table for a 2-bit LUT.

Table 7-2. 2-Bit LUT Truth Table

IN1	IN0	OUT
0	0	User defined
0	1	
1	0	
1	1	

Each 2-bit LUT has 4 bits in the OTP to define their output function.

7.3.3.2 3-Bit LUT Macro-Cell

When used to implement LUT functions, the 3-bit LUT takes in three input signals from the connection mux and produces a single output, which goes back into the connection mux.

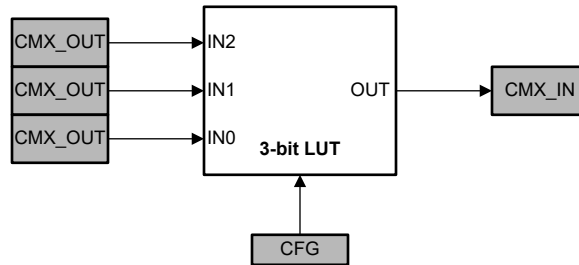


Figure 7-3. 3-Bit LUT Block Diagram

These LUTs can be configured to any 3-input user defined function, including the following standard digital logic functions: AND, NAND, OR, NOR, XOR, XNOR, INV.

Table 7-3 provides the truth tables for a 3-bit LUT.

Table 7-3. 3-Bit LUT Truth Table

IN2	IN1	IN0	OUT
0	0	0	User defined
0	0	1	
0	1	0	
0	1	1	
1	0	0	
1	0	1	
1	1	0	
1	1	1	

Each 3-bit LUT has 8 bits in the OTP to define their output function.

7.3.3.3 2-Bit LUT or D Flip-Flop or Latch Macro-Cell

This configurable use logic block can serve as either a 2-bit LUT, or as a D flip-flop/latch.

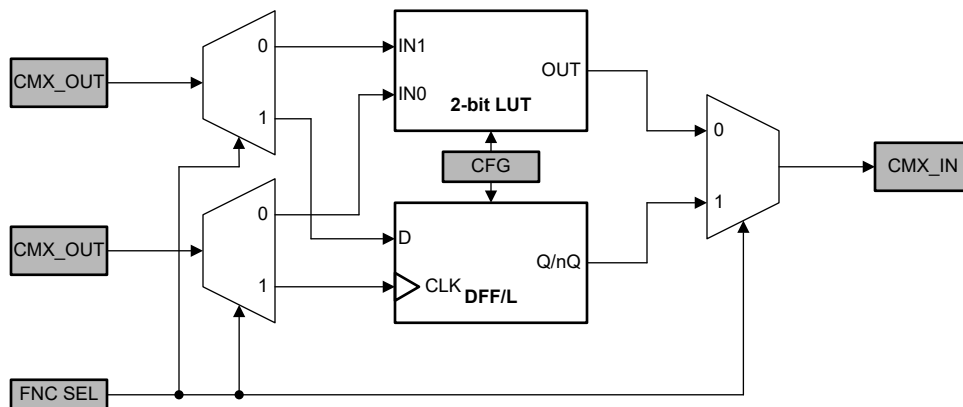


Figure 7-4. 2-Bit LUT or DFF or Latch Block Diagram

When used to implement LUT functions, the 2-bit LUT takes in two input signals from the connection mux and produces a single output, which goes back into the connection mux. These LUTs can be configured to any

2-input user defined function, including the following standard digital logic functions: AND, NAND, OR, NOR, XOR, XNOR, INV.

Table 7-4 provides the truth table for a 2-bit LUT.

Table 7-4. 2-Bit LUT Truth Table

IN1	IN0	OUT
0	0	User defined
0	1	
1	0	
1	1	

Each 2-bit LUT has 4 bits in the OTP to define their output function.

When used to implement a sequential logic element, the two input signals from the connection mux go to the data (D) and clock (CLK) inputs of the flip-flop/latch, with the output going back to the connection mux. This macro-cell has initial state parameters, as well as clock and output polarity parameters.

The operation of the D flip-flop/latch will follow the following functional descriptions:

- The clock polarity is configurable and can be set to non-inverted (CLKPOL = 0, CLK) or inverted (CLKPOL = 1, nCLK).
 - DFF with CLK: CLK is rising edge triggered, then Q = D; otherwise Q will not change.
 - DFF with nCLK: CLK is falling edge triggered, then Q = D; otherwise Q will not change.
 - Latch with CLK: when CLK is Low, then Q = D; otherwise Q remains its previous value (input D has no effect on the output, when CLK is High).
 - Latch with nCLK: when CLK is High, then Q = D; otherwise Q remains its previous value (input D has no effect on the output, when CLK is Low).
- The output polarity is configurable and can be set to non-inverted (Q) or inverted (nQ).

Table 7-5 and Table 7-6 provides the truth tables for the D flip-flop and D latch, respectively.

Table 7-5. D Flip-Flop Truth Table

CLKPOL	CLK	D	Q	nQ
0	↓	0	Q ₀	nQ ₀
	↑	0	0	1
	↓	1	Q ₀	nQ ₀
	↑	1	1	0
1	↓	0	0	1
	↑	0	Q ₀	nQ ₀
	↓	1	1	0
	↑	1	Q ₀	nQ ₀

Table 7-6. D Latch Truth Table

CLKPOL	CLK	D	Q	nQ
0	0	0	0	1
	1	0	Q ₀	nQ ₀
	0	1	1	0
	1	1	Q ₀	nQ ₀

Table 7-6. D Latch Truth Table (continued)

CLKPOL	CLK	D	Q	nQ
1	0	0	Q ₀	nQ ₀
	1	0	0	1
	0	1	Q ₀	nQ ₀
	1	1	1	0

7.3.3.4 3-Bit LUT or D Flip-Flop or Latch with Set or Reset Macro-Cell

This configurable use logic blocks can serve as either a 3-bit LUT, or as a D flip-flop/latch with a reset/set.

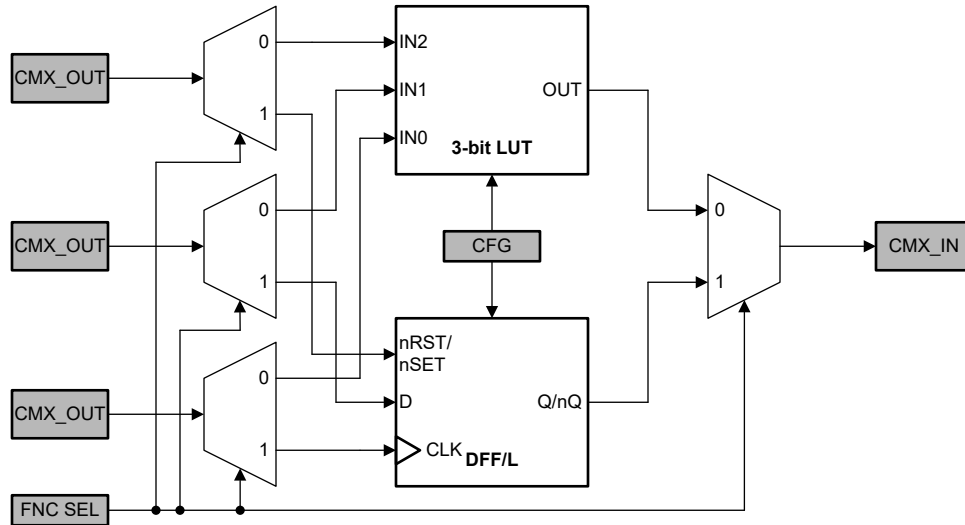


Figure 7-5. 3-Bit LUT or DFF or Latch With nRST or nSET Block Diagram

When used to implement LUT functions, the 3-bit LUT takes in three input signals from the connection mux and produces a single output, which goes back into the connection mux. These LUTs can be configured to any 3-input user defined function, including the following standard digital logic functions: AND, NAND, OR, NOR, XOR, XNOR, INV.

Table 7-7 provides the truth table for a 3-bit LUT.

Table 7-7. 3-Bit LUT Truth Table

IN2	IN1	IN0	OUT
0	0	0	User defined
0	0	1	
0	1	0	
0	1	1	
1	0	0	
1	0	1	
1	1	0	
1	1	1	

Each 3-bit LUT has 8 bits in the OTP to define their output function.

When used to implement a sequential logic element, the three input signals from the connection mux go to the data (D), clock (CLK), and reset/set (nRST/nSET) inputs for the flip-flop/latch, with the output going back to the connection mux. This macro-cell has initial state, clock polarity, reset/set polarity, and output polarity parameters.

The operation of the D flip-flop/latch will follow the following function descriptions:

- The clock polarity is configurable and can be set to non-inverted (CLKPOL = 0, CLK) or inverted (CLKPOL = 1, nCLK).
 - DFF with CLK: CLK is rising edge triggered, then Q = D; otherwise Q will not change.
 - DFF with nCLK: CLK is falling edge triggered, then Q = D; otherwise Q will not change.
 - Latch with CLK: when CLK is Low, then Q = D; otherwise Q remains its previous value (input D has no effect on the output, when CLK is High).
 - Latch with nCLK: when CLK is High, then Q = D; otherwise Q remains its previous value (input D has no effect on the output, when CLK is Low).
- These DFF/latches have an option for an active-low reset/set.
 - nRST: when the input is high, the DFF/latch is in normal operation; and when low, Q is reset to 0.
 - nSET: when the input is high, the DFF/latch is in normal operation; and when low, Q is set to 1.
- If reset/set is not desired, users may tie this input to V_{CC} or another constant high source.
- The output polarity is configurable and can be set to non-inverted (Q) or inverted (nQ).

Table 7-8 and Table 7-9 provides the truth tables for the D flip-flop and D latch with reset/set, respectively.

Table 7-8. D Flip-Flop with nRST or nSET Truth Table

nRST	nSET	CLKPOL	CLK	D	Q	nQ
0	—	0	X	X	0	1
—	0		X	X	1	0
1	1		↓	0	Q ₀	nQ ₀
			↑	0	0	1
			↓	1	Q ₀	nQ ₀
↑	1		1	1	0	
0	—	1	X	X	0	1
—	0		X	X	1	0
1	1		↓	0	0	1
			↑	0	Q ₀	nQ ₀
			↓	1	1	0
↑	1		1	Q ₀	nQ ₀	

Table 7-9. D Latch With nRST/nSET Truth Table

nRST	nSET	CLKPOL	CLK	D	Q	nQ
0	—	0	X	X	0	1
—	0		X	X	1	0
1	1		0	0	0	1
			1	0	Q ₀	nQ ₀
			0	1	1	0
1	1		1	1	Q ₀	nQ ₀

Table 7-9. D Latch With nRST/nSET Truth Table (continued)

nRST	nSET	CLKPOL	CLK	D	Q	nQ
0	—	1	X	X	0	1
—	0		X	X	1	0
1	1		0	0	Q ₀	nQ ₀
			1	0	0	1
			0	1	Q ₀	nQ ₀
			1	1	1	0

7.3.3.5 3-Bit LUT or Pipe Delay Macro-cell

This macro-cell can serve as either a 3-bit LUT or as a pipe delay.

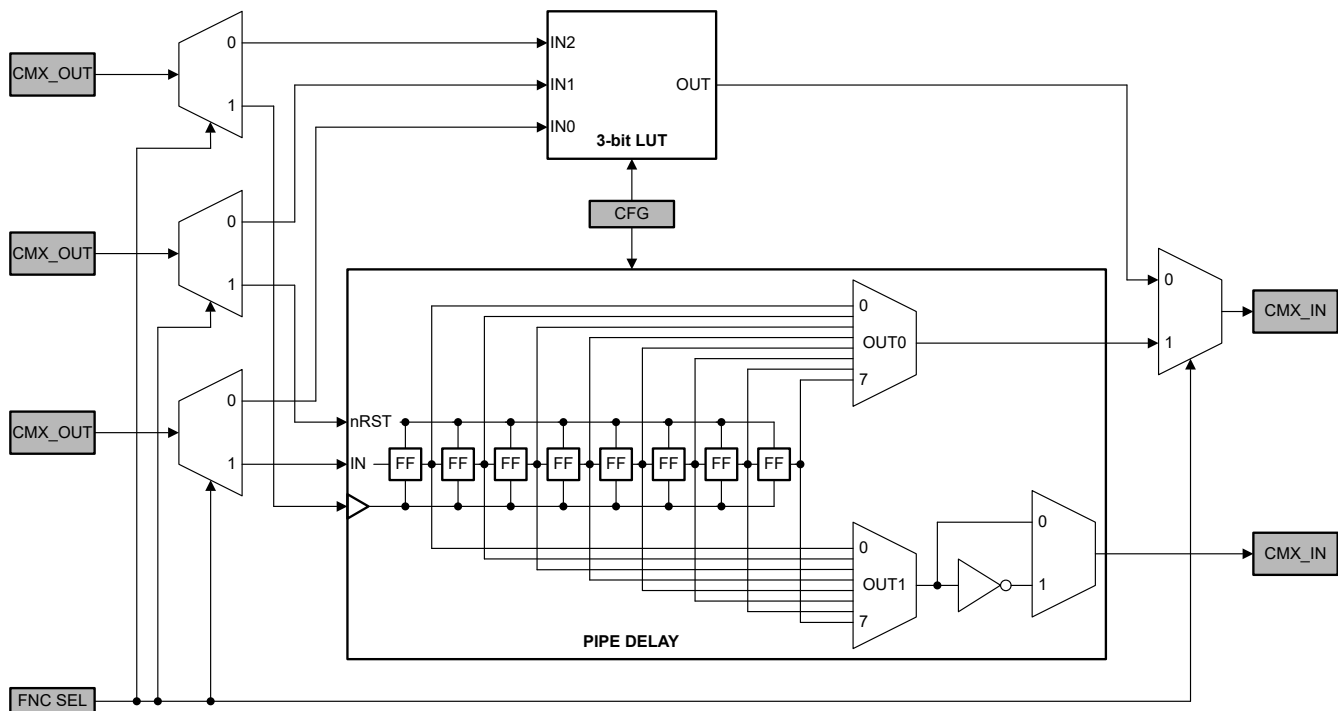


Figure 7-6. 3-Bit LUT or Pipe Delay Block Diagram

When used to implement LUT functions, the 3-bit LUT takes in three input signals from the connection mux and produces a single output, which goes back into the connection mux. These LUTs can be configured to any 3-input user defined function, including the following standard digital logic functions: AND, NAND, OR, NOR, XOR, XNOR, INV.

Table 7-10 provides the truth table for a 3-bit LUT.

Table 7-10. 3-Bit LUT Truth Table

IN2	IN1	IN0	OUT
0	0	0	User defined
0	0	1	
0	1	0	
0	1	1	
1	0	0	
1	0	1	
1	1	0	
1	1	1	

Each 3-bit LUT has 8 bits in the OTP to define their output function.

When used to implement a pipe delay, the three input signals from the connection mux go to the delay input (IN), clock (CLK), and reset (nRST) inputs for the flip-flop/latch, with two outputs going back to the connection mux. With this macro-cell, users can select the number of delay stages per output (from 1 to 8) and the output polarity for OUT1.

The pipe delay is an 8-stage delay composed of 8 DFFs. The DFF cells are tied in series where the output of each delay cell goes to the next DFF cell. There are delay output points for each set of the OUT0 and OUT1 outputs to a mux that is used to control the selection of the amount of delay for each pipe delay output.

For normal pipe delay functionality, the nRST input should be high. If nRST input is low, the pipe delay macro-cell is in a reset state and all outputs are low.

Figure 7-7 shows an example of the pipe delay macro-cell with 2 stages of delay selected.

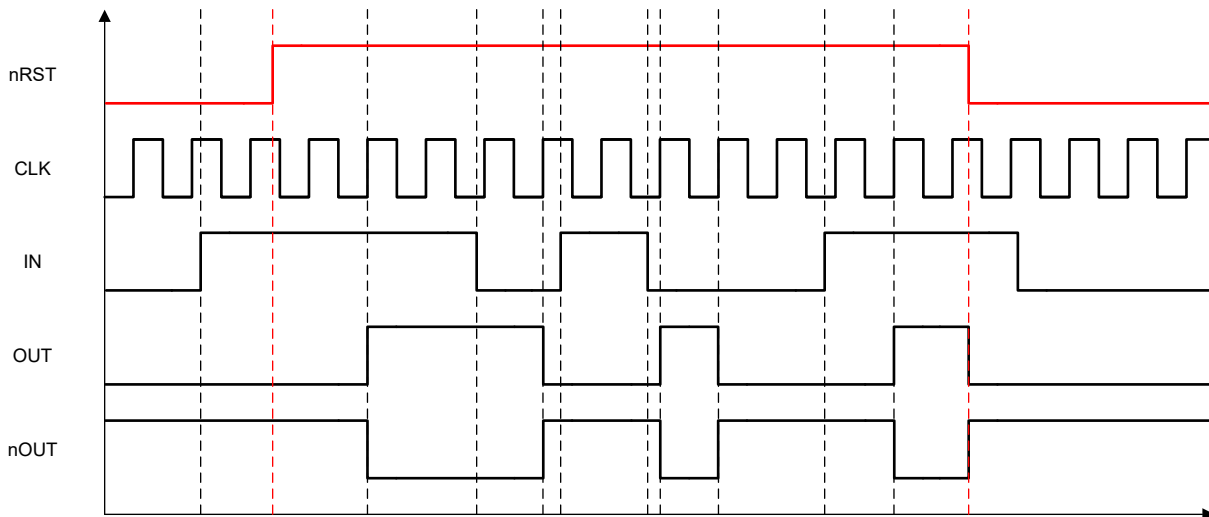


Figure 7-7. Pipe Delay Macro-Cell Timing Example (Delay = 2)

7.3.3.6 4-Bit LUT or 8-Bit Counter or Delay Macro-Cell

This macro-cell can serve as either a 4-bit LUT or as a counter/delay generator (CNT/DLY).

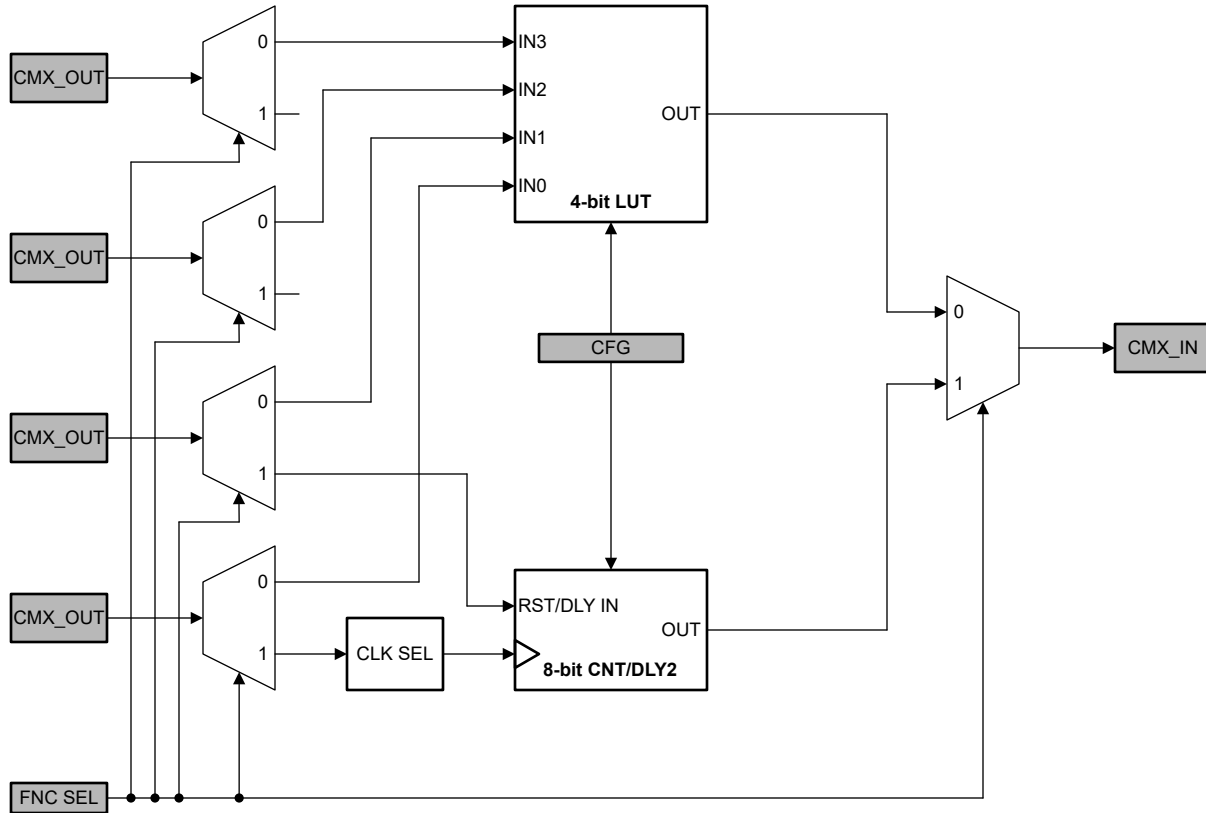


Figure 7-8. 4-Bit LUT or 8-Bit CNT/DLY Block Diagram

When used to implement LUT functions, the 4-bit LUT takes in four input signals from the connection mux and produces a single output, which goes back into the connection mux. This LUT can be configured to any 4-input user defined function, including the following standard digital logic functions: AND, NAND, OR, NOR, XOR, XNOR, INV.

Table 7-11 provides the truth table for a 4-bit LUT.

Table 7-11. 4-Bit LUT Truth Table

IN3	IN2	IN1	IN0	OUT
0	0	0	0	User defined
0	0	0	1	
0	0	1	0	
0	0	1	1	
0	1	0	0	
0	1	0	1	
0	1	1	0	
0	1	1	1	
1	0	0	0	
1	0	0	1	
1	0	1	0	
1	0	1	1	
1	1	0	0	
1	1	0	1	
1	1	1	0	
1	1	1	1	

Each 4-bit LUT has 16 bits in the OTP to define their output function.

When used to implement 8-bit counter/delay function, the two input signals from the connection mux go to the clock (CLK) and reset (RST/DLY IN) for the counter/delay macro-cell, with the output going back to the connection mux. As a counter, the macro-cell counts to the given data value and generates a pulse when it reaches the set value or is reset. As a delay, it postpones rising or falling edges for the duration that is a function of the register value.

For more information on CNT/DLY macro-cell, see [Section 7.3.4](#).

7.3.4 8-Bit Counters and Delay Generators (CNT/DLY)

The counters/delay generators are 8-bit, supporting counter data values from 1 to 255. For flexibility, the clock source for each of these macro-cells can be configured as the internal oscillator, a divided clock derived from an oscillator (OSC/4, /12, /24, /64, /4096), or an external clock source coming from the connection mux. There is also the option to chain from the output of the previous CNT/DLY macro-cell to implement longer counter/delay circuits. Note that the counter/delay macro-cell is rising edge triggered, that is the counter will increment/decrement on rising clock edges.

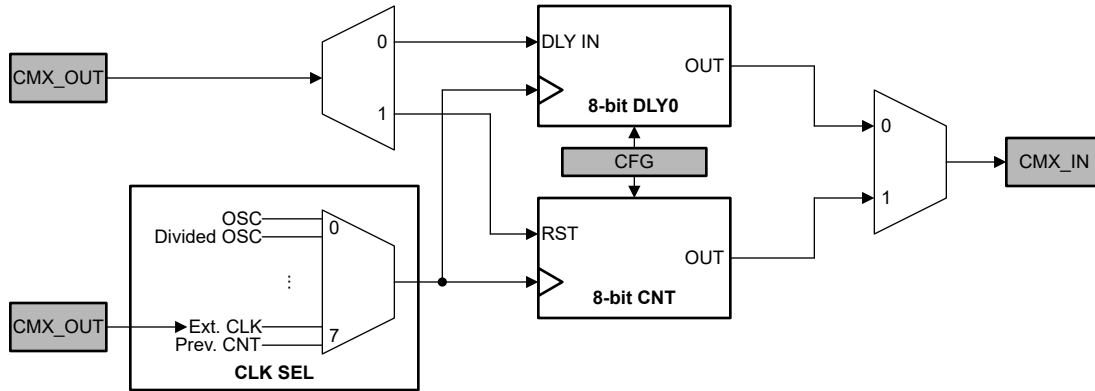


Figure 7-9. CNT/DLY Block Diagram

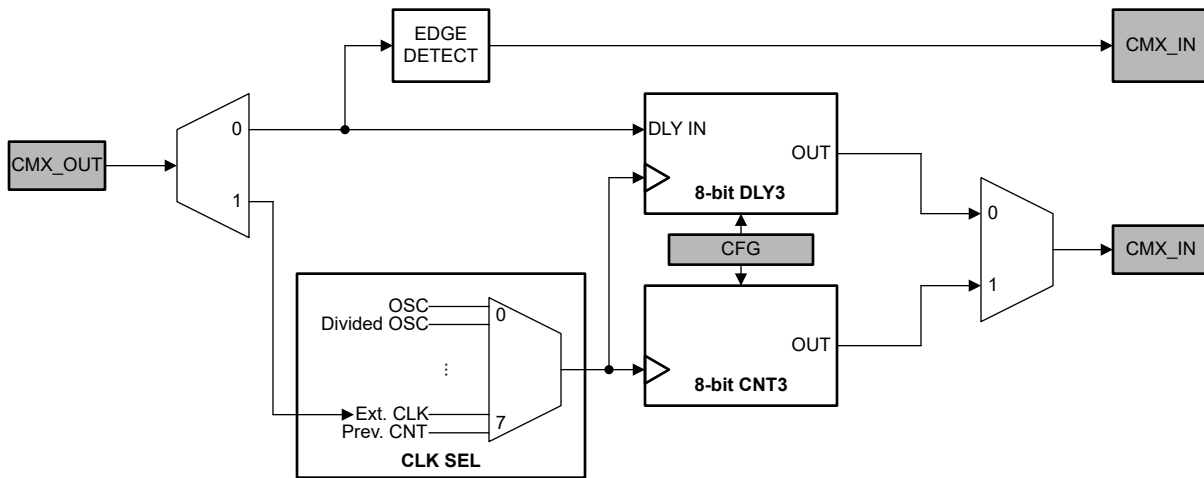


Figure 7-10. CNT/DLY3 Block Diagram

As a counter/delay (CNT/DLY) macro-cell, users may select from the following modes: delay, counter.

DLY3 also has an optional edge detector that will generate a short pulse on the specified edge in addition to the delayed output.

7.3.4.1 Delay Mode

When configured as a Delay generator (DLY), this macro-cell delays the input based on counter DATA and CLK input frequency and postpones rising and/or falling edges. The edge on which to delay is selected by the Edge select parameter and can be configured as:

- **Rising:** only delay on rising edges of IN.
- **Falling:** only delay on falling edges of IN.
- **Both:** delay on both rising and falling edges of IN.

For delay applications, it is recommended to use larger counter data values for less error. If an input pulse width is shorter than the specified delay time, the pulse will be filtered out. This feature can be useful for deglitching.

If the on-chip oscillator is used, a delay error or offset is introduced depending on whether the OSC is set to "forced power on" or "auto power on". An additional 2 clock cycles are included in the delay calculation for clock synchronization, but there is an option to bypass the clock sync.

The delay time is calculated by $DELAY = (DATA + (t_{d_err} \text{ or } t_{d_os}) + 2)/f_{CLK}$.

When the OSC is set to "auto power on" and DLY macro-cells are triggered subsequently before the previous output is present, the OSC will continue to clock and the DLY will begin on the next rising edge. Thus, the subsequent delays can be calculated as if the OSC were set to "forced power on".

Figure 7-11 shows an example of the Delay macro-cell operation set to both edge delay and data = 1.

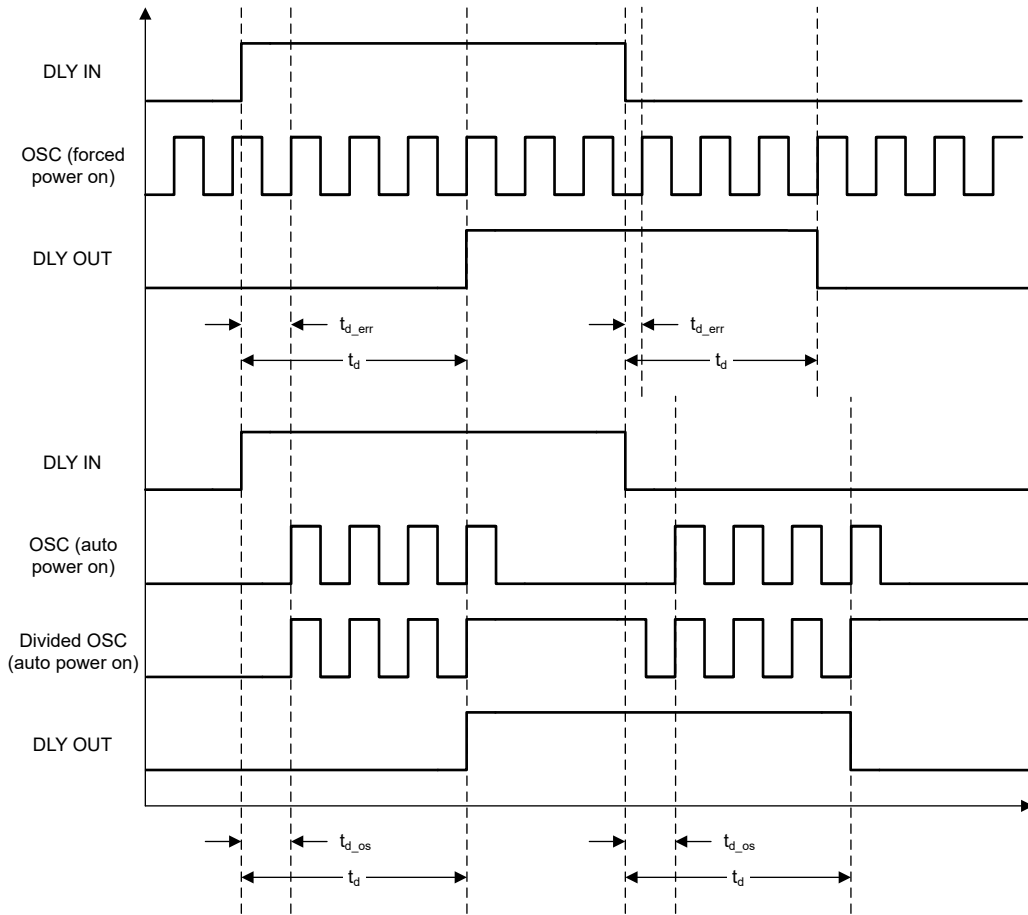


Figure 7-11. Delay output timing example (Both edge delay and DATA = 1)

Figure 7-12 shows an example timing of two different Delay macro-cells triggered consecutively with the OSC set to "auto power on".

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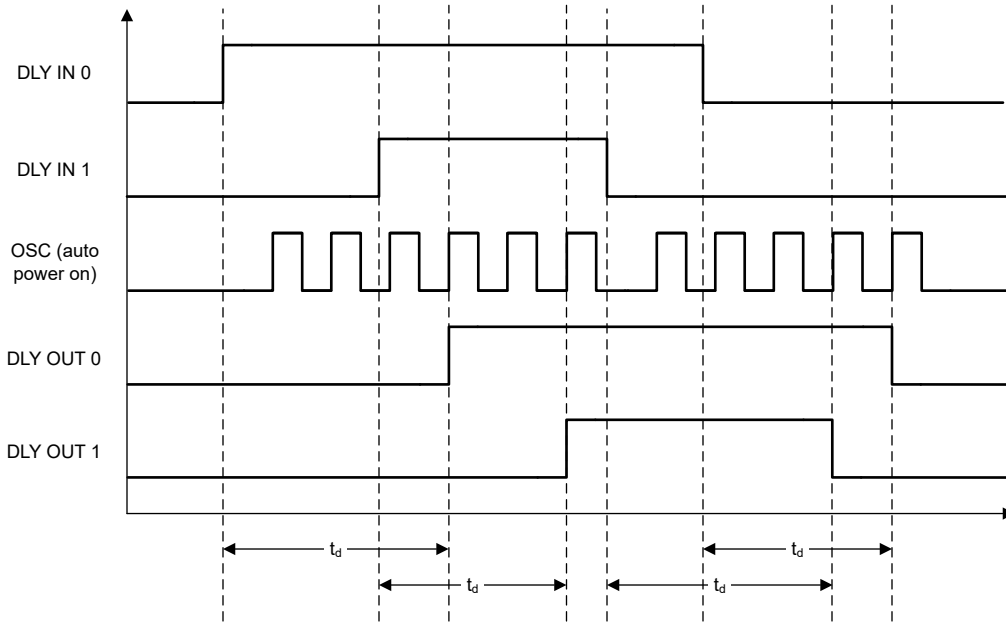


Figure 7-12. Delay output timing example (2 Delay macro-cells, Both edge delay, DATA = 1, OSC power = auto)

7.3.4.2 Reset Counter Mode

When configured as a Counter (CNT) and a valid edge appears on the IN input, this macro-cells resets the internal counter to 0 and begins counting down from DATA on the next rising clock edge. Then, the macro-cell outputs a pulse for the duration of one CLK period when the count reaches 0 and wrap around to the value in DATA. The counter will continually operate until another reset is received. The edge on which the Counter is reset is determined by the Edge select parameter and can be configured as:

- **Rising:** only rising edges of IN reset the counter.
- **Falling:** only falling edges of IN reset the counter.
- **Both:** both rising and falling edges of IN reset the counter.
- **High Level Reset:** the counter is reset to 0 whenever IN is High; after reset, the counter output stays Low until the next rising CLK edge, then operates normally.

The counter time is calculated by $COUNT = (DATA + 1)/f_{CLK}$. After a reset, an additional 2 clock cycles is added for clock synchronization, but there is an option to bypass the clock sync.

Note

Counters are initialized with DATA = 0 after POR.

Figure 7-13 and Figure 7-14 show examples of Counter output timing diagrams with respect to the Edge select parameter with DATA = 1 and DATA = 3, respectively.

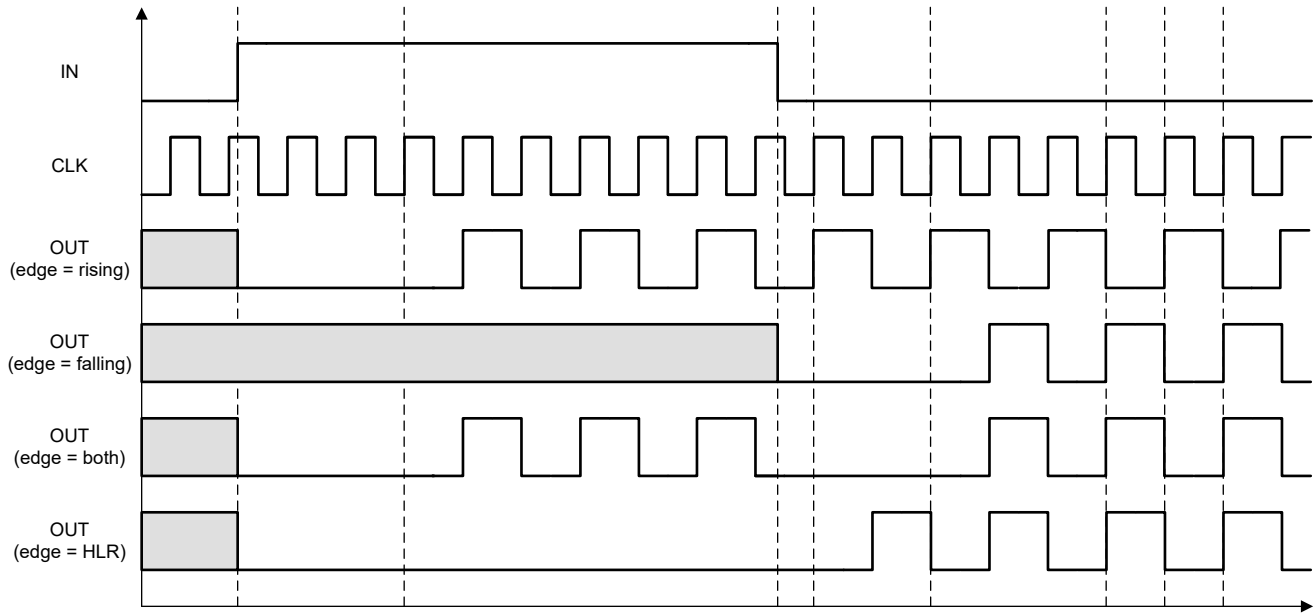


Figure 7-13. Counter output timing example (DATA = 1)

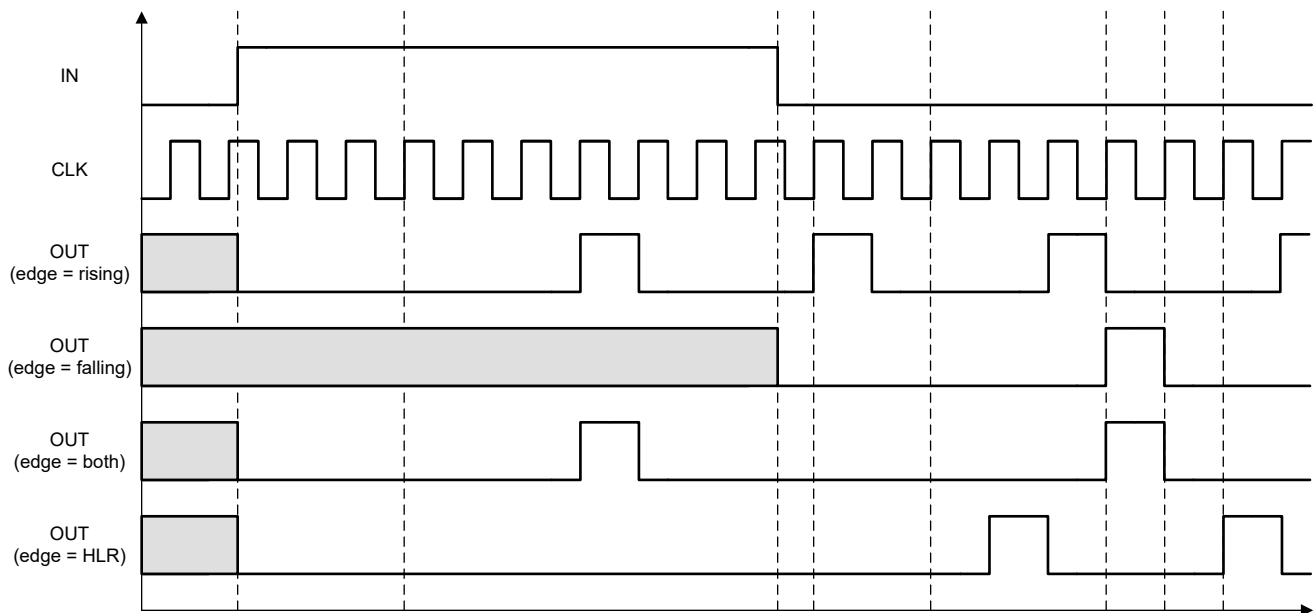


Figure 7-14. Counter output timing example (DATA = 3)

Figure 7-15 shows an example of how the Counter macro-cell operates when the IN signal is shorter than the counter length (shown when edge select parameter is set to "both").

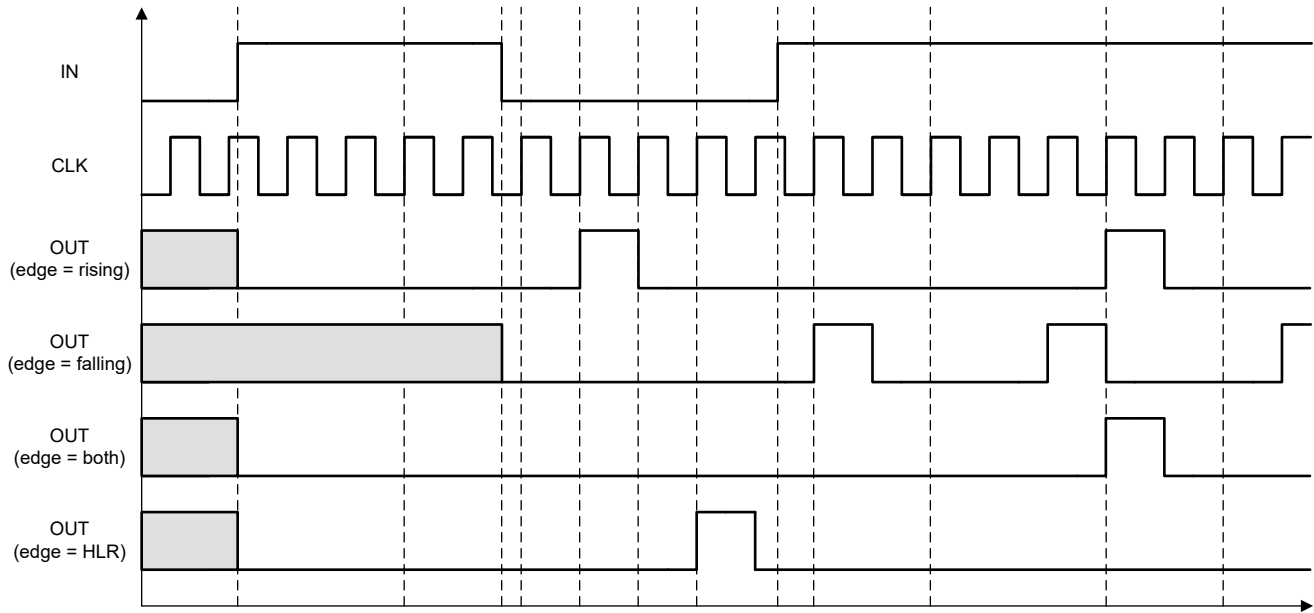


Figure 7-15. Counter output timing example with RST < DATA (DATA = 3)

7.3.5 Programmable Deglitch Filter or Edge Detector Macro-cell

The TPLD1201-Q1 has one macro-cell that can be configured as a programmable filter (PFLT) or edge detector (EDET). The PFLT macro-cell can be used to generate a delay (t_{pflt_d}) characterized by t_{pflt_pw} and t_{pflt_pd} . t_{pflt_pw} can be set to 125ns, 250ns, 375ns, or 500ns and t_{pflt_pd} is a fixed value at ≈ 40 ns. Furthermore, the output of the macro-cell can be configured to one of four options: rising edge detection, falling edge detection, both edge detection, or both edge delay. Lastly, the filter operates as a short low-pass filter and its output can be set as non-inverted or inverted.

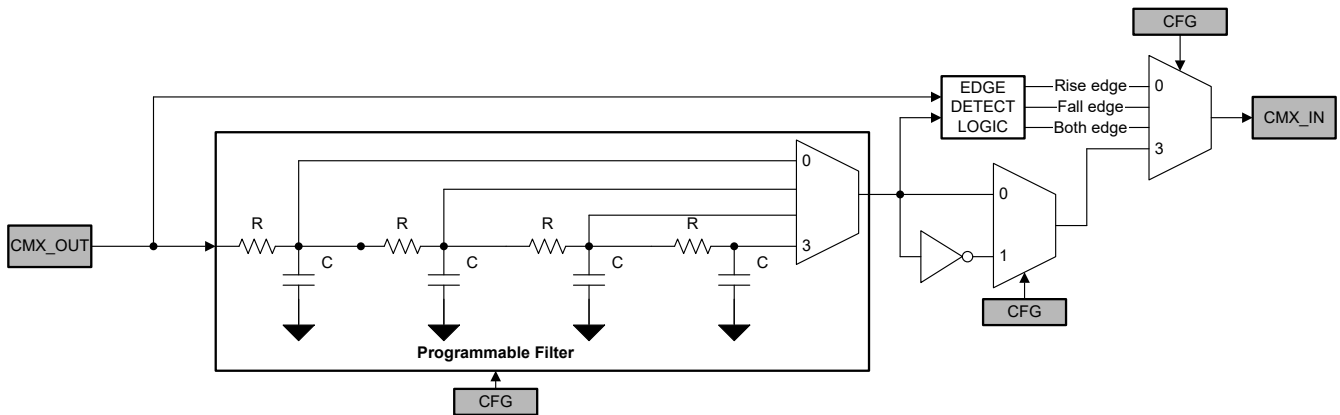


Figure 7-16. Programmable Filter and Edge Detector Block Diagram

Note

The input signal must be longer than t_{pflt_d} , otherwise it will be filtered out.

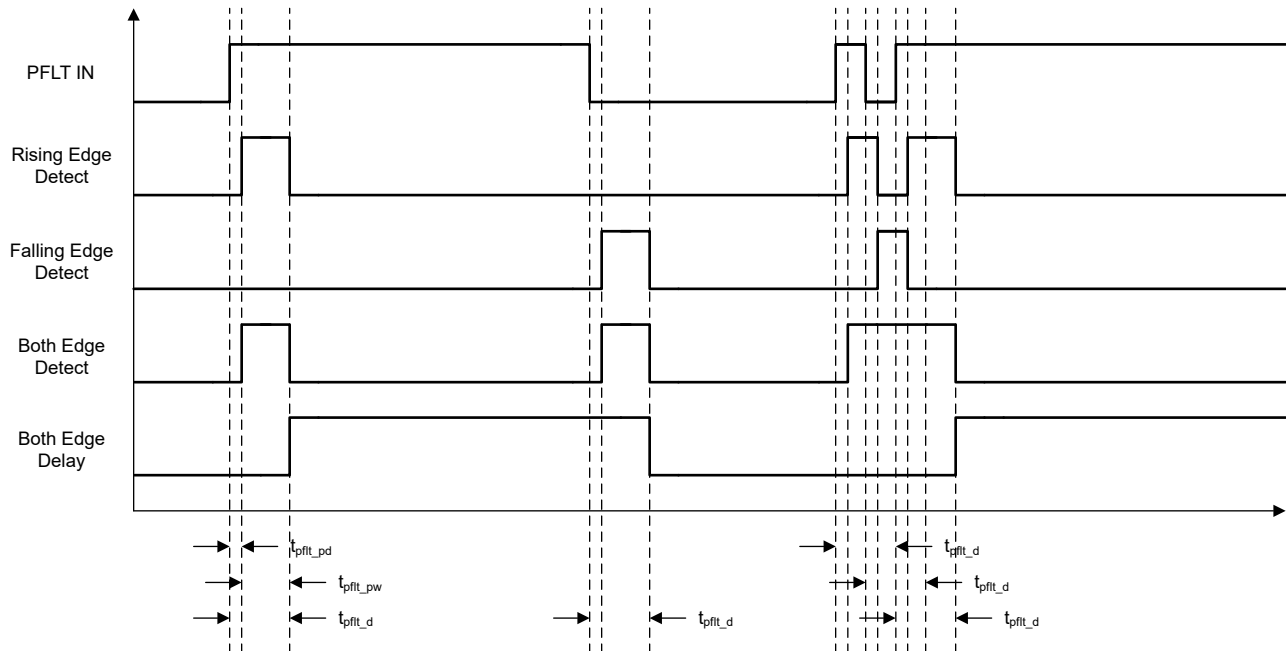


Figure 7-17. Programmable Filter and Edge Detector Output Timing Diagram Example

7.3.6 Selectable Frequency Oscillator

The TPLD1201-Q1 has one internal oscillator, selectable to operate at 25kHz or at 2MHz. The user can select one of these operating frequencies for the OSC macro-cell, or the internal oscillator could be bypassed and the operating frequency can come from an external clock.

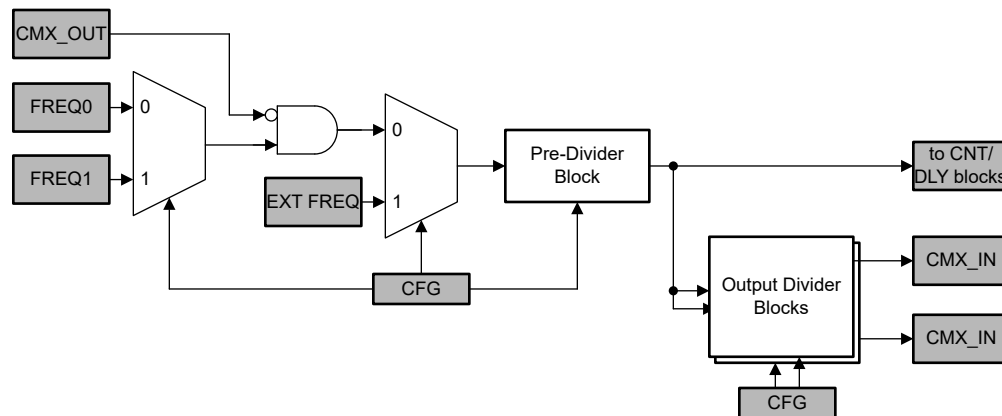


Figure 7-18. Oscillator Block Diagram

Following the operating clock input, there are two divider stages that allow users the flexibility of various clock frequencies for use throughout the device.

The first stage divider allows the selection of up to four options from the operating oscillator frequency as listed in [Table 7-13](#). The output of the first divider stage is routed directly to the counter/delay generator macro-cell CLK inputs, where a separate second divider stage is available.

The output of the first divider stage is also routed into a second divider stage within the oscillator macro-cell. The oscillator macro-cell has two separate second stage dividers, allowing for the output of two separate clocks (OUT0 and OUT1) into the connection mux. See [Table 7-14](#)

Oscillator power modes: When using the device's internal oscillator, there are two configuration settings available:

- **Force power on:** the internal oscillator will continuously run as long as the device is powered on.
- **Auto power on:** the internal oscillator will dynamically power on when any macro-cell requests the oscillator directly from the pre-divider block output and not through the connection mux, and then power off once the task is complete.
- **External power on/off:** the internal oscillator will be powered down when PDWN is asserted High. PDWN signal takes priority over the oscillator power modes. This is only applicable when the internal oscillator is selected and is bypassed when an external clock is used.

Table 7-12. Frequency Options and Limits

Frequency Option	MIN	TYP	MAX
FREQ0	23.75kHz	25kHz	26.25kHz
FREQ1	1.9MHz	2MHz	2.1MHz
EXT	-	-	-

Table 7-13. Oscillator Pre-dividers

Pre-Divider Option	Magnitude
P0	1
P1	2
P2	4
P3	8

Table 7-14. Oscillator Output Dividers

Output Divider Options	Magnitude
OD0	1
OD1	2
OD2	3
OD3	4
OD4	8
OD5	12
OD6	24
OD7	64

7.3.7 Analog Comparators (ACMP)

There are two analog comparator (ACMP) macro-cells in the TPLD1201-Q1. The analog comparator compares two voltages (IN+ and IN-) and outputs a digital signal (OUT) indicating which input is larger, a High signal for IN+ and a Low for IN-.

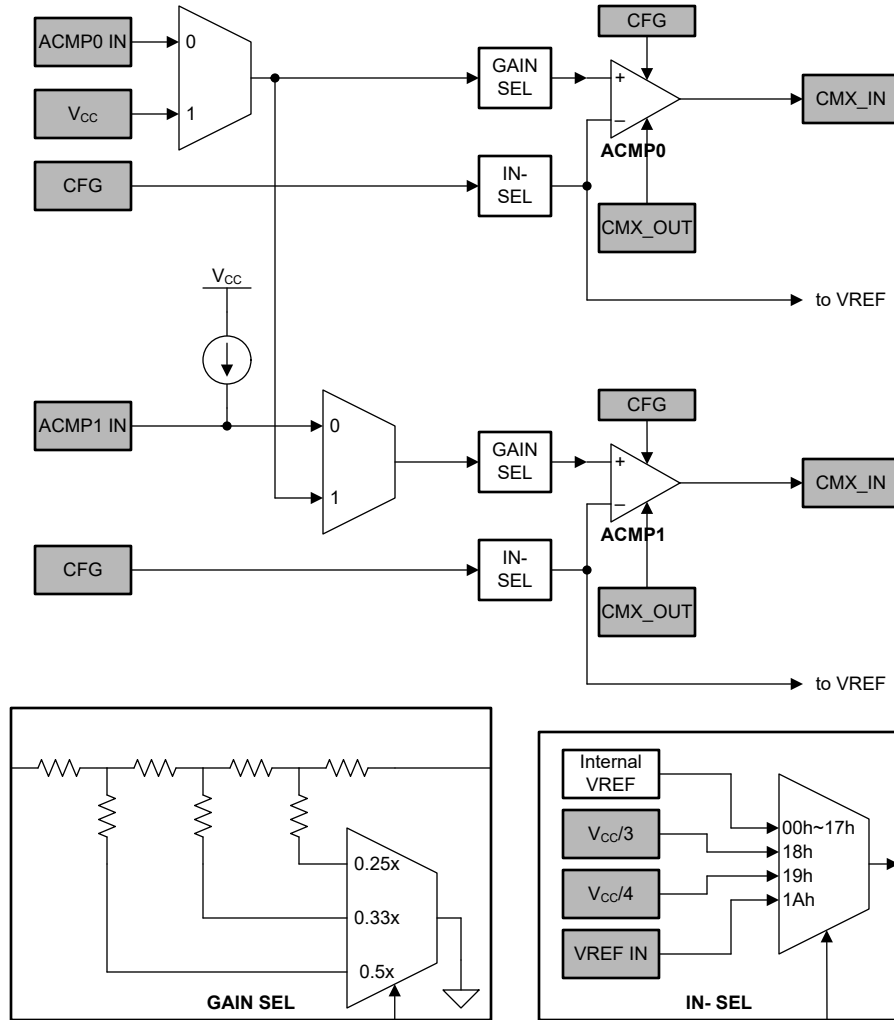


Figure 7-19. ACMP Block Diagram

For the ACMP macro-cell to operate, the power up signal (PWR UP) needs to be asserted high. By connecting to signals coming from the connection mux, it is possible to have each ACMP always on, always off, or switched on dynamically based on a digital signal coming from the connection mux. When powered down, the ACMP will output a low signal.

- PWR UP = 1: ACMP is powered up.
- PWR UP = 0: ACMP is powered down.

Upon power-up, the ACMP output will remain low, and then become valid 100 μ s (typical) after POR signal goes high. During this time, ensure the internal oscillator is not powered down.

Each of the ACMP cells has a positive input signal that can be provided by a variety of external sources with a selectable gain stage before going into the analog comparator. ACMP1 also has a 100 μ A pullup current source option for external sensor excitation purposes. The negative input signal is either created from an internal VREF or from an external source.

Table 7-15. ACMP0 and ACMP1 Input Sources

Parameters	ACMP0 ⁽¹⁾	ACMP1 ⁽²⁾
IN+ source	Analog Input 0 (shared with IO1)	Analog Input 1 (shared with IO4)
	V _{CC}	ACMP0 IN+

Table 7-15. ACMP0 and ACMP1 Input Sources (continued)

Parameters	ACMP0 ⁽¹⁾	ACMP1 ⁽²⁾
IN- source	50mV	50mV

	1200mV	1200mV
	V _{CC} /3	V _{CC} /3
	V _{CC} /4	V _{CC} /4
	VREF Analog Input (shared with IO2)	VREF Analog Input (shared with IO2)

(1) Positive Analog input source to ACMP.

(2) Negative Analog input source to ACMP. Internal VREF thresholds are optimized near 1200mV.

IN+ gain: Each of the ACMP cells has a positive input signal that can be provided by a variety of external sources, and can also have a selectable gain stage (1X, 0.5X, 0.33X, 0.25X) before connection to the analog comparator.

IN- voltage range: 50mV to 1.2V through the internal VREF, V_{CC}/3, V_{CC}/4, or external source.

Hysteresis: Each ACMP has four selectable hysteresis options 0mV, 25mV, 50mV and 200mV. The hysteresis is selectable if the internal VREF macro-cell or an external VREF input is used.

- **0mV:** will disable the input signal hysteresis.
- **25mV:** is a +12.5mV and -12.5mV hysteresis. For VREF = 1V, the trigger points will be 1.0125V and 0.9875V.
- **50mV:** is a +25mV and -25mV hysteresis. For VREF = 1V, the trigger points will be 1.025V and 0.975V.
- **200mV:** is a +100mV and -100mV hysteresis. For VREF = 1V, the trigger points will be 1.1V and 0.9V.

If hysteresis is desired, ensure the hysteresis is less than the VREF, otherwise the negative trigger point will be pushed below device ground which may stress the device beyond the Recommended Operating Conditions and reduce the lifetime of the device. For example, if VREF is set to 50mV and V_{HYS} is 200mV, the trigger points will be 150mV and -50mV.

Low bandwidth: The ACMP cell has a selection for the bandwidth of the input signal, which can be used to save power and reduce noise impact when lower bandwidth signals are being compared.

If V_{CC}/3 and V_{CC}/4 are not used at ACMP negative input, they can be disabled to reduce power consumption.

7.3.8 Voltage Reference (VREF)

The voltage reference (VREF) produces a fixed (constant) voltage, providing references to the analog comparators and external circuitry. The TPLD1201-Q1 has a voltage reference macro-cell to provide references to the two analog comparators. This macro-cell can supply a user selection of fixed voltage references, /2, /3 and /4 reference off of the V_{CC} power supply to the device, and externally supplied voltage references from the VREF Analog Input (shared with IO4). The macro-cell also has the option to output a reference voltage on the VREF Analog Output (shared with IO7).

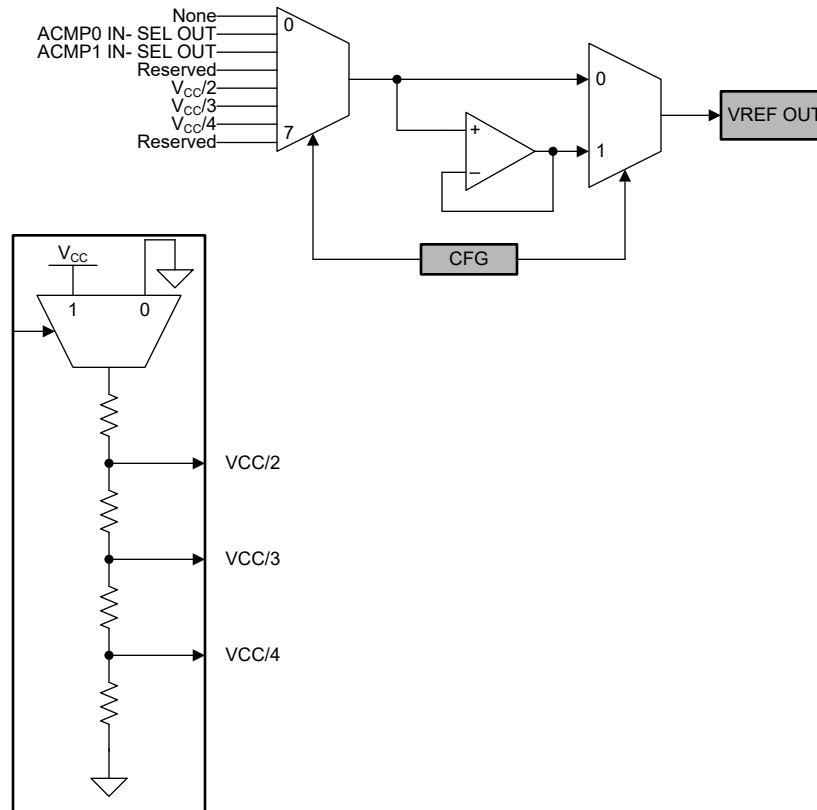


Figure 7-20. Voltage Reference Block Diagram

If $V_{CC}/2$, $V_{CC}/3$, and $V_{CC}/4$ are not used at VREF select, they can be disabled to reduce power consumption.

Force bandgap on keeps the bandgap on while the chip is powered.

Output active buffer parameter enables the active output buffer on VREF.

Table 7-16. VREF Range

V_{CC}	VREF Range
1.71V - 5.5V	50mV - 1.2V

7.4 Device Functional Modes

7.4.1 Power-On Reset

The TPLD1201-Q1 has a power-on reset (POR) macro-cell that provides correct device initialization and operation of all macro-cells in the device. The purpose of the POR circuit is to have consistent behavior and predictable results when the V_{CC} power is first ramping to the device, and also while the V_{CC} is falling during power-down. To accomplish this goal, the POR drives a defined sequence of internal events that trigger changes to the states of different macro-cells inside the device, and finally to the state of the I/O pins.

The power-on Reset (POR) macro-cell will produce a logic High signal as an output when the device power supply (V_{CC}) rises to approximately V_{PORR} and device completely starts up. All outputs are in high impedance state and chip starts loading data from OTP. The reset signal is released for internal macro-cells and all the registers are initialized to their default states. [Figure 7-21](#) shows POR system generates a sequence of signals that enable certain macro-cells.

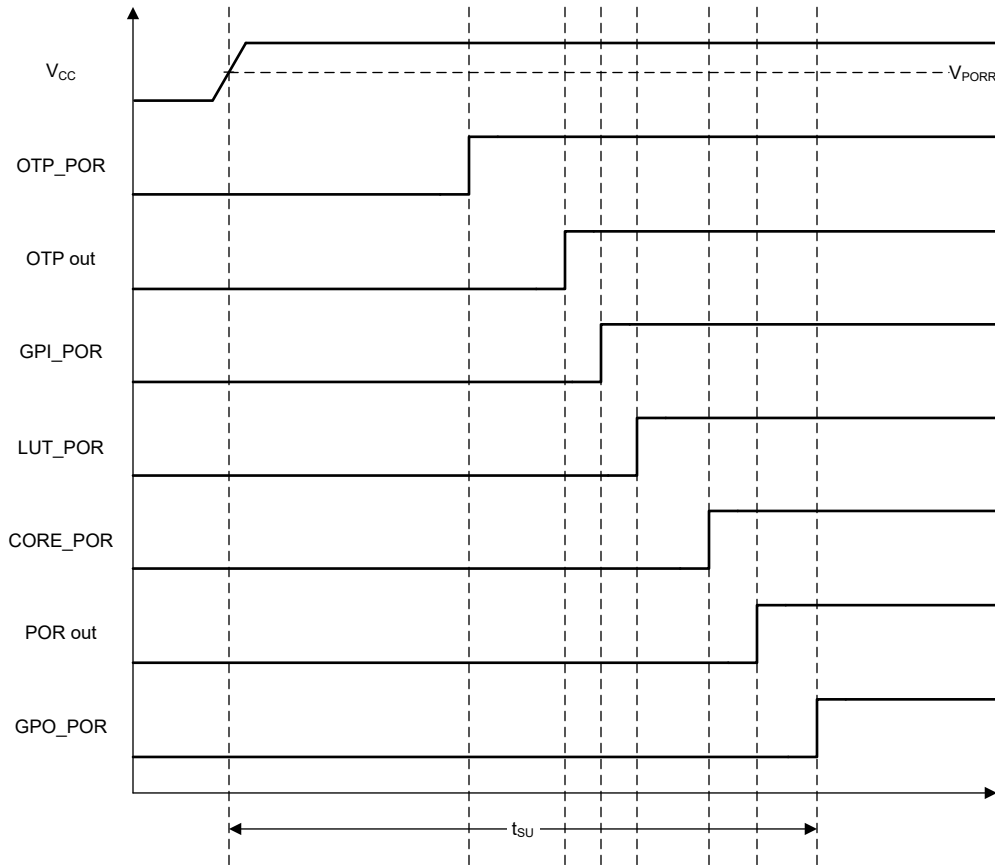


Figure 7-21. POR Sequence

As shown in [Figure 7-21](#), after the V_{CC} has start ramping up and crosses the V_{PORR} threshold:

- First, the on-chip OTP memory is reset.
- Next, the device reads the data from OTP memory, and transfers this information to configure each macro-cell and the connection mux.
- The third stage resets the GPIOs that are configured as inputs and then enables them.
- After that, the LUTs are reset and become active. After LUTs, the delay cells, OSC, DFFs, latches and pipe delay are initialized.
- After all macro-cells are initialized, the internal POR signal generated by the POR macro-cell goes from low to high.
- The last portion of the device to be initialized are the output PINs, which transition from high impedance to active at this point.

Delay blocks will pass their inputs through to the output during the startup sequence without delaying the signal per the configuration, so a LUT added in front of the input of a DLY that ANDs the DLY input with POR will cause the input signal to not appear until the device has fully powered up.

GPIO quick charge: There is an option to connect a 2kΩ resistor in parallel to any configured pull up/pull down resistors to help inputs get to the right voltage faster, especially if there is significant capacitance. The 10kΩ, 100kΩ and 1MΩ GPIO pull up/pull down resistors are not enabled until the POR sequence is completed.

Initialization: All internal macro-cells are initialized to a low level by default. Starting from when V_{CC} exceeds V_{PORR} , macro-cells in the TPLD1201-Q1 are powered on and forced into a reset state.

The VREF output pin driving signal can precede POR output signal going high by 3μs to 5μs. The POR signal going high indicates the mentioned power-up sequence is complete.

8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

8.1 Application Information

The configurable logic and timing blocks of TPLD1201-Q1 allow for the device to provide symmetric power-up and power-down signals for numerous components. In this application the device is configured to output the maximum amount of power-up and power-down sequencing signals based on a counter/delay macro-cell.

8.2 Typical Application

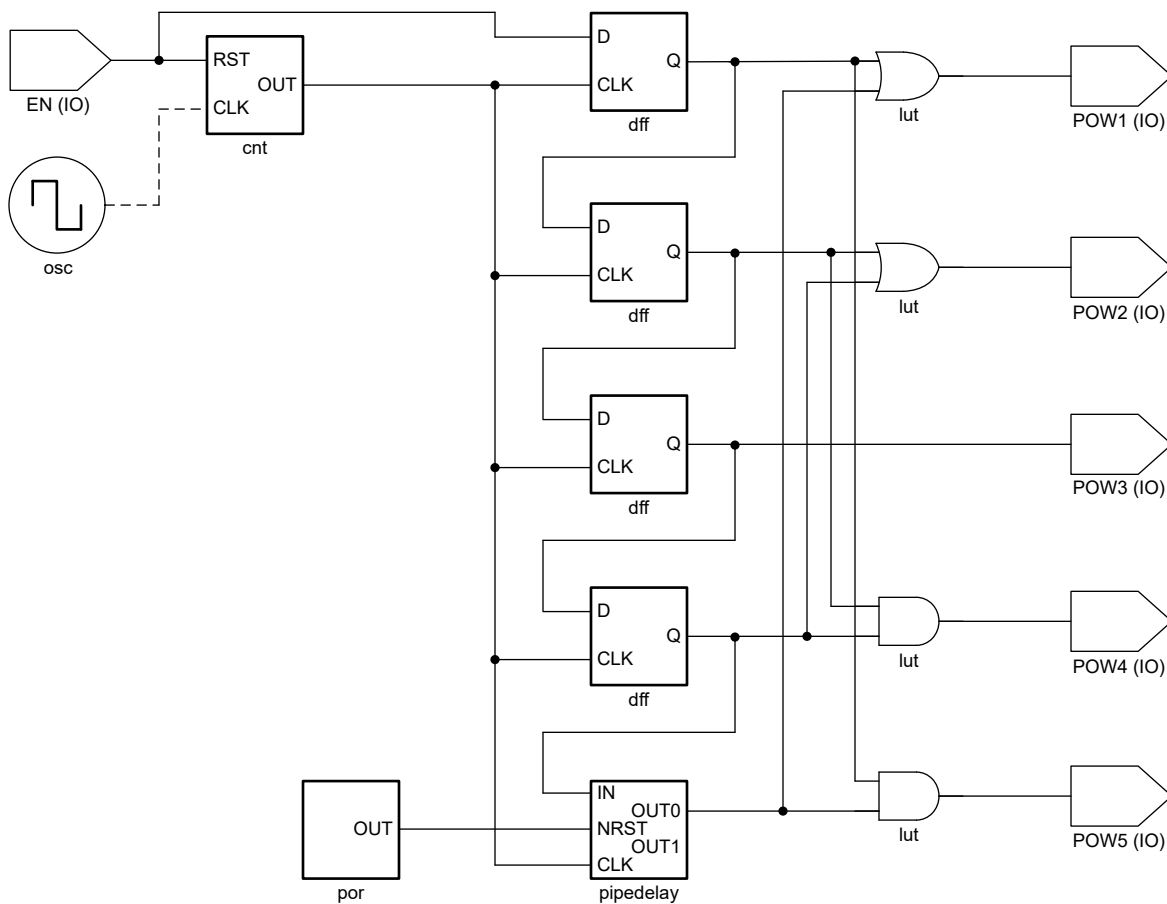


Figure 8-1. Typical Application Block Diagram in InterConnect Studio

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8.2.1 Design Requirements

8.2.1.1 Power Considerations

Ensure the desired supply voltage is within the range specified in the *Recommended Operating Conditions*. The supply voltage sets the device's electrical characteristics of the device as described in the *Electrical Characteristics* section.

The positive voltage supply must be capable of sourcing current equal to the total current to be sourced by all outputs of the TPLD1201-Q1 plus the maximum static supply current, I_{CC} , listed in the *Electrical Characteristics*, and any transient current required for switching. The device can only source as much current that is provided by the positive supply source. Ensure the maximum total current through V_{CC} listed in the *Absolute Maximum Ratings* is not exceeded.

The ground must be capable of sinking current equal to the total current to be sunk by all outputs of the TPLD1201-Q1 plus the maximum supply current, I_{CC} , listed in the *Electrical Characteristics*, and any transient current required for switching. The logic device can only sink as much current that can be sunk into its ground connection. Ensure the maximum total current through GND listed in the *Absolute Maximum Ratings* is not exceeded.

The TPLD1201-Q1 can drive a load with a total capacitance less than or equal to 15pF while still meeting all of the data sheet specifications. Larger capacitive loads can be applied; however, it is not recommended to exceed 15pF.

The TPLD1201-Q1 can drive a load with total resistance described by $R_L \geq V_O / I_O$, with the output voltage and current defined in the *Electrical Characteristics* table with V_{OH} and V_{OL} . When outputting in the HIGH state, the output voltage in the equation is defined as the difference between the measured output voltage and the supply voltage at the V_{CC} pin.

Total power consumption can be calculated using the information provided in [CMOS Power Consumption and Cpd Calculation](#).

Thermal increase can be calculated using the information provided in [Thermal Characteristics of Standard Linear and Logic \(SLL\) Packages and Devices](#).

CAUTION

The maximum junction temperature, $T_{J(max)}$ listed in the *Absolute Maximum Ratings*, is an additional limitation to prevent damage to the device. Do not violate any values listed in the *Absolute Maximum Ratings*. These limits are provided to prevent damage to the device.

8.2.1.2 Input Considerations

Input signals must cross $V_{IL(max)}$ or $V_{t-(min)}$ to be considered a logic LOW, and $V_{IH(min)}$ or $V_{t+(max)}$ to be considered a logic HIGH. Do not exceed the maximum input voltage range found in the *Absolute Maximum Ratings*.

Unused inputs must be terminated to either V_{CC} or ground. The unused inputs can be directly terminated if the input is completely unused, or they can be connected with a pull-up or pull-down resistor if the input will be used sometimes, but not always. A pull-up resistor is used for a default state of HIGH, and a pull-down resistor is used for a default state of LOW. The drive current of the controller, leakage current into the TPLD1201-Q1 (as specified in the *Electrical Characteristics*), and the desired input transition rate limits the resistor size. A 10k Ω resistor value is often used due to these factors.

The TPLD1201-Q1 has CMOS inputs and thus requires fast input transitions to operate correctly, as defined in the *Recommended Operating Conditions* table. Slow input transitions can cause oscillations, additional power consumption, and reduction in device reliability.

The TPLD1201-Q1 can be used with no signal transition rate requirements because it has Schmitt-Trigger inputs.

Another benefit to having Schmitt-Trigger inputs is the ability to reject noise. Noise with a large enough amplitude can still cause issues. To know how much noise is too much, please refer to the $\Delta V_{T(min)}$ in the *Electrical Characteristics*. This hysteresis value will provide the peak-to-peak limit.

Unlike what happens with standard CMOS inputs, Schmitt-Trigger inputs can be held at any valid value without causing huge increases in power consumption. The typical additional current caused by holding an input at a value other than V_{CC} or ground is plotted in the *Typical Characteristics*.

Refer to the *Feature Description* section for additional information regarding the inputs for this device.

8.2.1.3 Output Considerations

The positive supply voltage is used to produce the output HIGH voltage. Drawing current from the output will decrease the output voltage as specified by the V_{OH} specification in the *Electrical Characteristics*. The ground voltage is used to produce the output LOW voltage. Sinking current into the output will increase the output voltage as specified by the V_{OL} specification in the *Electrical Characteristics*.

Push-pull outputs that could be in opposite states, even for a very short time period, should never be connected directly together. This can cause excessive current and damage to the device.

Two channels within the same device with the same input signals can be connected in parallel for additional output drive strength.

Open-drain outputs can be connected together directly to produce a wired-AND configuration or for additional output drive strength.

Unused outputs can be left floating. Do not connect outputs directly to V_{CC} or ground.

Refer to the *Feature Description* section for additional information regarding the outputs for this device.

8.2.2 Detailed Design Procedure

1. Add a decoupling capacitor from V_{CC} to GND. The capacitor needs to be placed physically close to the device and electrically close to both the V_{CC} and GND pins. An example layout is shown in the *Layout* section.
2. Ensure the capacitive load at the output is $\leq 50\text{pF}$. This is not a hard limit; by design, however, it will optimize performance. This can be accomplished by providing short, appropriately sized traces from the TPLD1201-Q1 to one or more of the receiving devices.
3. Ensure the resistive load at the output is larger than $(V_{CC} / I_{O(max)})\Omega$. Doing this will prevent the maximum output current from the *Absolute Maximum Ratings* from being violated. Most CMOS inputs have a resistive load measured in $\text{M}\Omega$; much larger than the minimum calculated previously.
4. Thermal issues are rarely a concern for logic gates; the power consumption and thermal increase, however, can be calculated using the steps provided in the application report, [CMOS Power Consumption and Cpd Calculation](#).

8.2.3 Application Curves

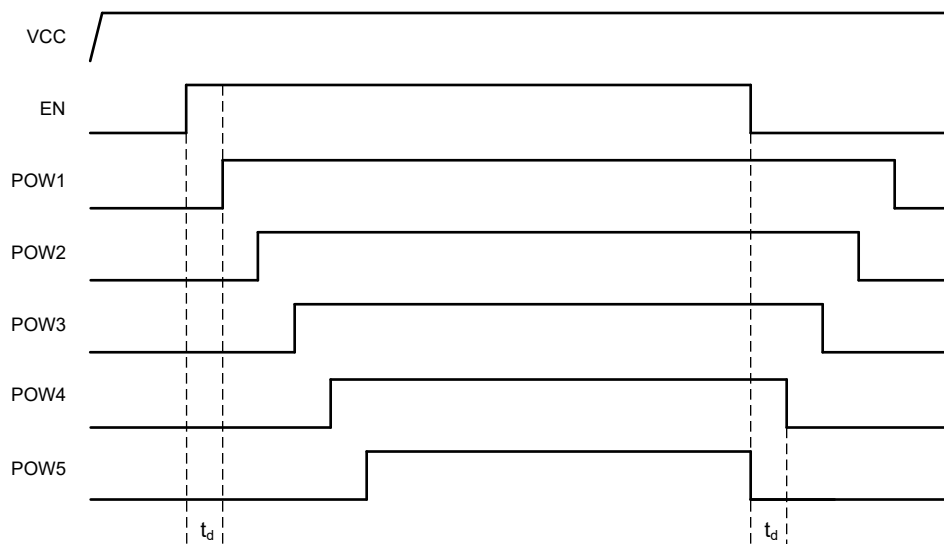


Figure 8-2. Application Timing Diagram

8.3 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. A $0.1\mu\text{F}$ capacitor is recommended for this device. It is acceptable to parallel multiple bypass capacitors to reject different frequencies of noise. The $0.1\mu\text{F}$ and $1\mu\text{F}$ capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

8.4 Layout

8.4.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices, inputs must never be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or V_{CC} , whichever makes more sense for the logic function or is more convenient.

8.4.2 Layout Example

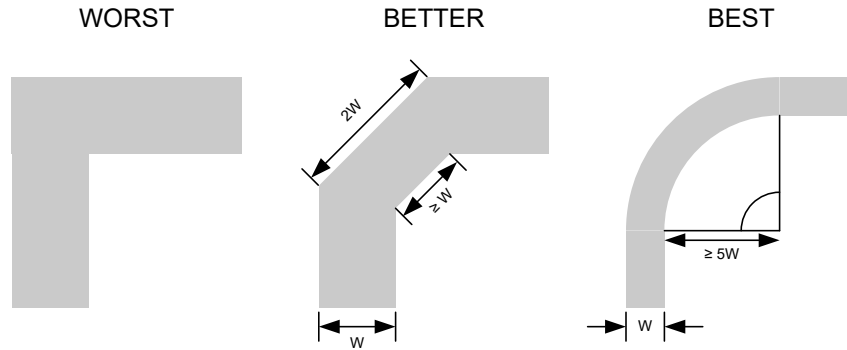


Figure 8-3. Example trace corners for improved signal integrity

ADVANCE INFORMATION

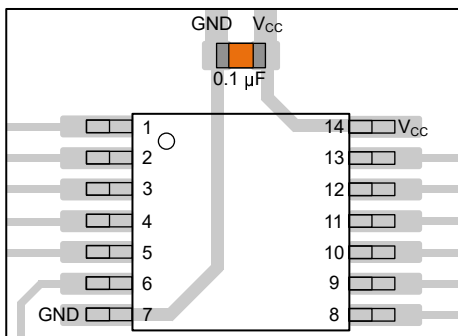


Figure 8-4. Example bypass capacitor placement for TSSOP and similar packages

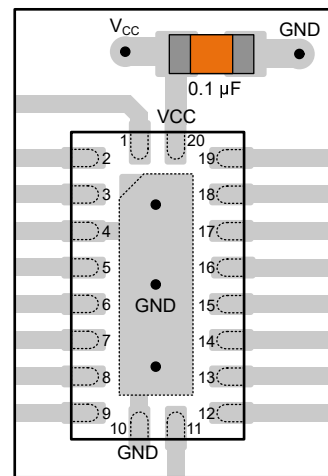


Figure 8-5. Example bypass capacitor placement for WQFN and similar packages

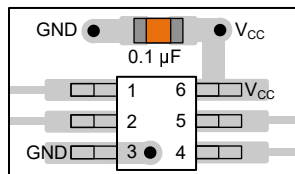


Figure 8-6. Example bypass capacitor placement for SOT, SC70 and similar packages

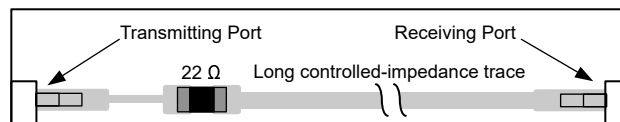


Figure 8-7. Example damping resistor placement for improved signal integrity

9 Device and Documentation Support

9.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on [ti.com](https://www.ti.com). Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

9.2 Support Resources

[TI E2E™ support forums](#) are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's [Terms of Use](#).

9.3 Trademarks

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All trademarks are the property of their respective owners.

9.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

9.5 Glossary

[TI Glossary](#) This glossary lists and explains terms, acronyms, and definitions.

10 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Date	Revision	Notes
September 2024	*	Advance Information release

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

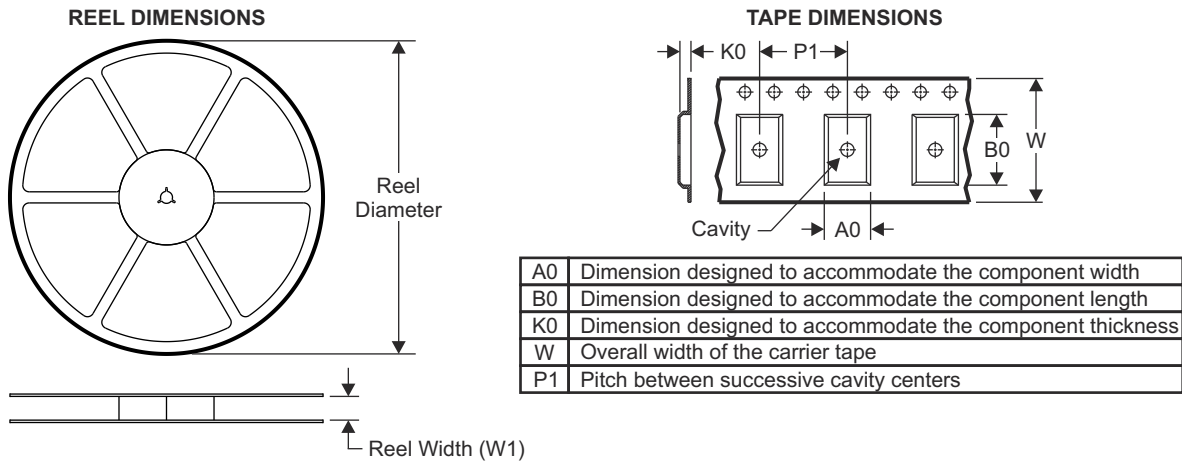
11.1 Packaging Option Addendum

Packaging Information

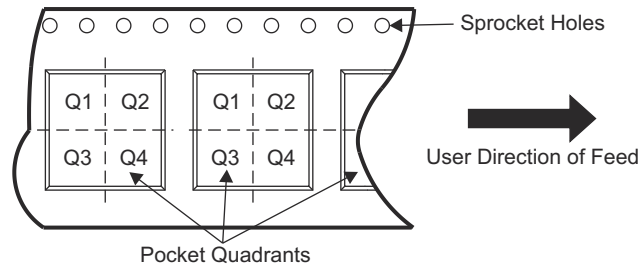
Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	Eco Plan ⁽²⁾	Lead/Ball Finish ⁽⁴⁾	MSL Peak Temp ⁽³⁾	Op Temp (°C)	Device Marking ⁽⁵⁾ ⁽⁶⁾
PTPLD1201DGSQ1	PREVIEW	VSSOP	DGS	10	3000	RoHS & Green	SN	Level-1-260C-UNLIM	-40 to 125	3M3S

- (1) The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.
LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PRE_PROD Unannounced device, not in production, not available for mass market, nor on the web, samples not available.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.
- (2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check <http://www.ti.com/productcontent> for the latest availability information and additional product content details.
TBD: The Pb-Free/Green conversion plan has not been defined.
Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.
Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.
Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)
- (3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.
- (5) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device
- (6) Multiple Device markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
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 In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

11.2 Tape and Reel Information



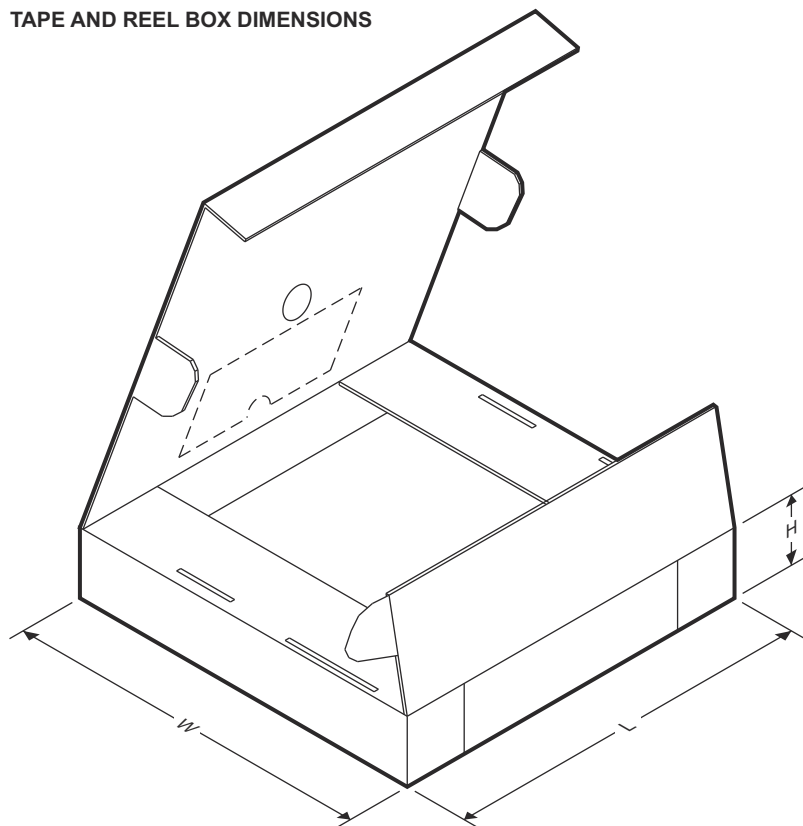
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
PTPLD1201DGSQ1	VSSOP	DGS	10	3000	330	12.4	5.3	3.4	1.4	8	12	1

ADVANCE INFORMATION

TAPE AND REEL BOX DIMENSIONS



ADVANCE INFORMATION

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
PTPLD1201DGSQ1	VSSOP	DGS	10	3000	356	356	35

11.3 Mechanical Data

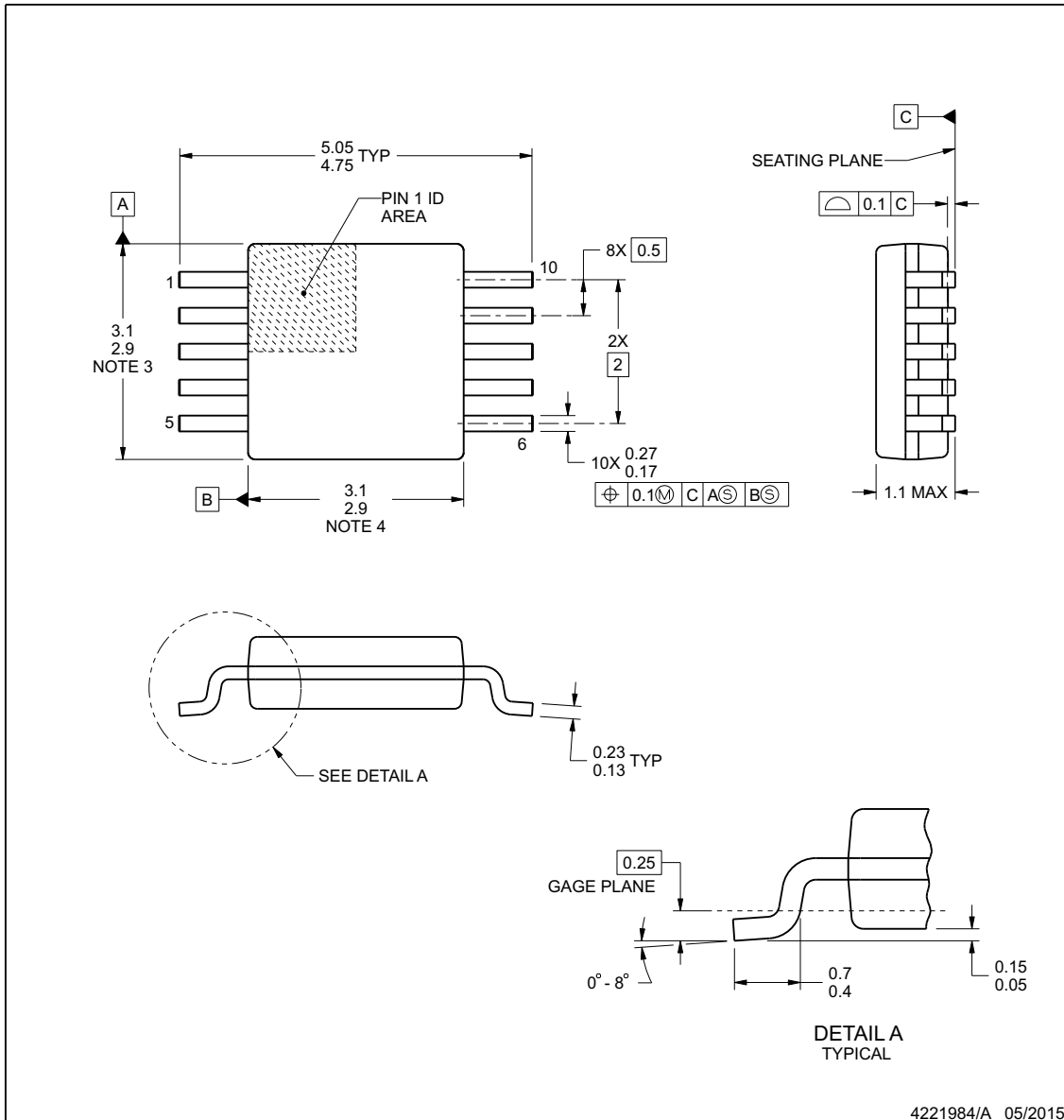


PACKAGE OUTLINE

DGS0010A

VSSOP - 1.1 mm max height

SMALL OUTLINE PACKAGE



NOTES:

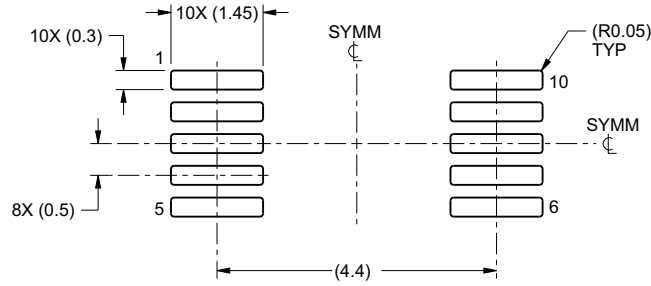
1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
5. Reference JEDEC registration MO-187, variation BA.

EXAMPLE BOARD LAYOUT

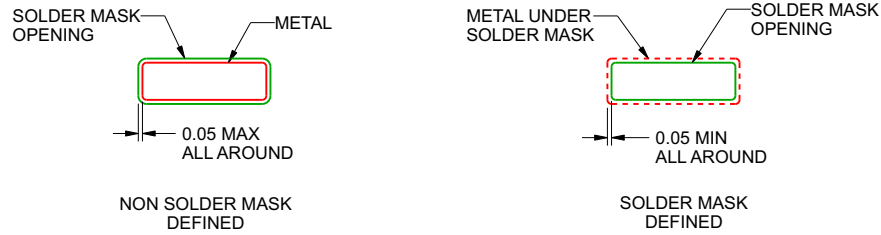
DGS0010A

VSSOP - 1.1 mm max height

SMALL OUTLINE PACKAGE



LAND PATTERN EXAMPLE
 SCALE:10X



SOLDER MASK DETAILS
 NOT TO SCALE

4221984/A 05/2015

NOTES: (continued)

- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

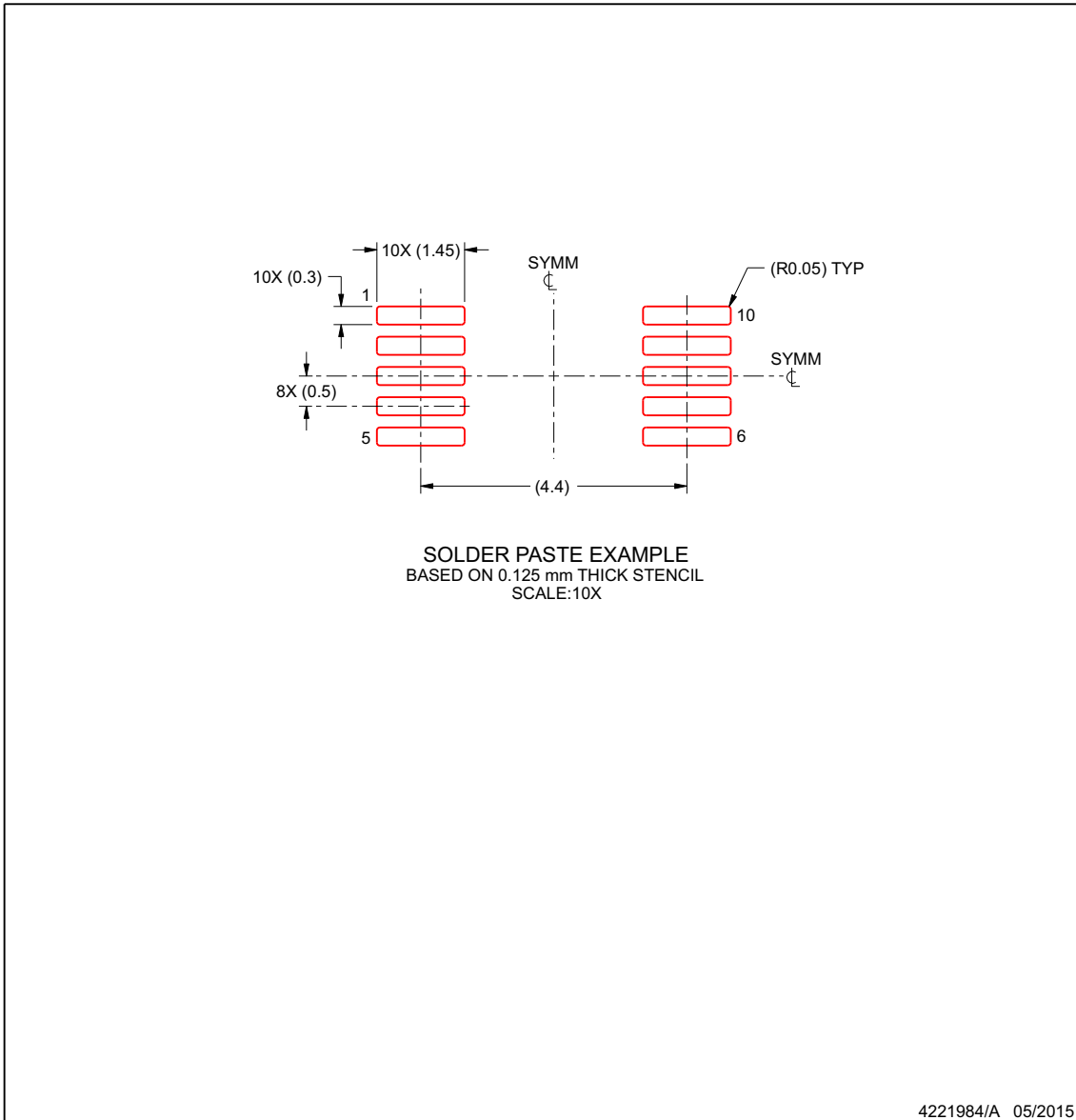
ADVANCE INFORMATION

EXAMPLE STENCIL DESIGN

DGS0010A

VSSOP - 1.1 mm max height

SMALL OUTLINE PACKAGE



NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

www.ti.com

ADVANCE INFORMATION

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
PTPLD1201DGSRQ1	ACTIVE	VSSOP	DGS	10	3000	TBD	Call TI	Call TI	-40 to 125		Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSELETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "-" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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OTHER QUALIFIED VERSIONS OF TPLD1201-Q1 :

- Catalog : [TPLD1201](#)

NOTE: Qualified Version Definitions:

- Catalog - TI's standard catalog product

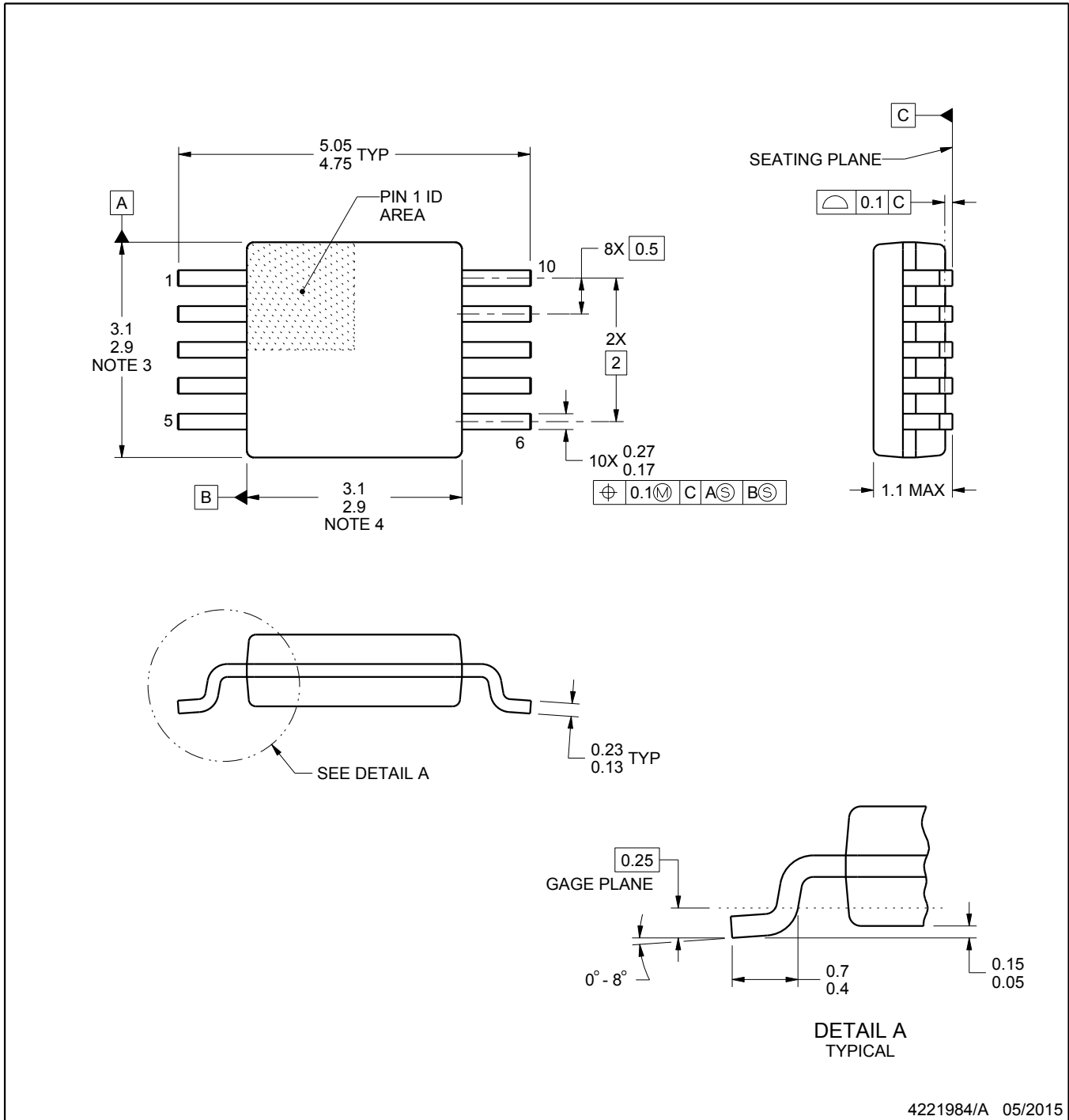
DGS0010A



PACKAGE OUTLINE

VSSOP - 1.1 mm max height

SMALL OUTLINE PACKAGE



4221984/A 05/2015

NOTES:

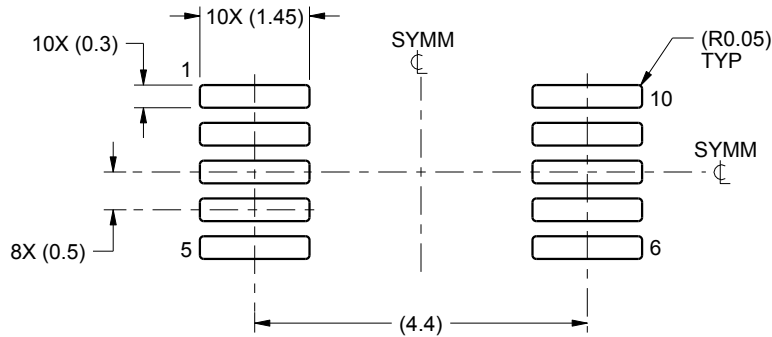
1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
5. Reference JEDEC registration MO-187, variation BA.

EXAMPLE BOARD LAYOUT

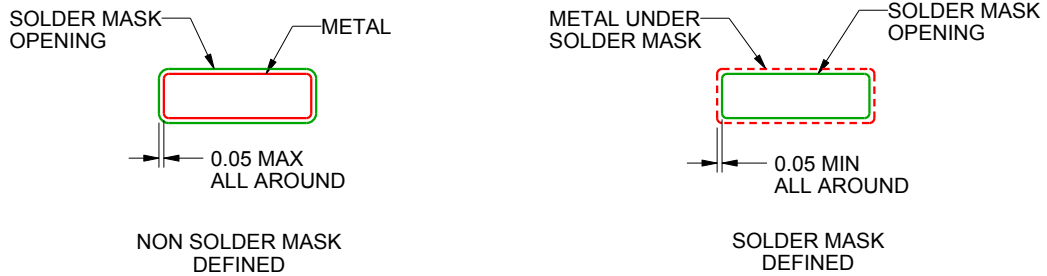
DGS0010A

VSSOP - 1.1 mm max height

SMALL OUTLINE PACKAGE



LAND PATTERN EXAMPLE
SCALE:10X



SOLDER MASK DETAILS
NOT TO SCALE

4221984/A 05/2015

NOTES: (continued)

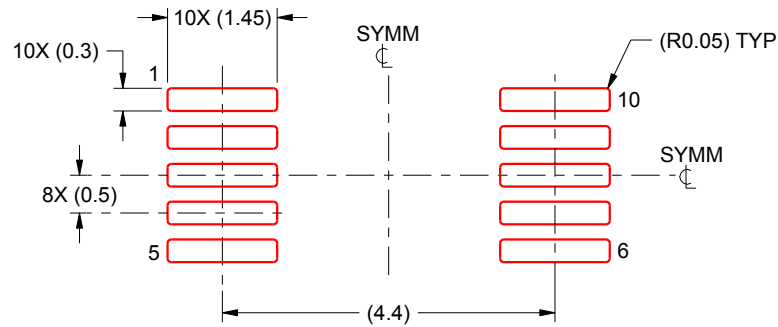
- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

DGS0010A

VSSOP - 1.1 mm max height

SMALL OUTLINE PACKAGE



SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE:10X

4221984/A 05/2015

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

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